

Small Scale Testing within a Correlative Multi-scale Framework

Phil Withers, Joao Fonseca

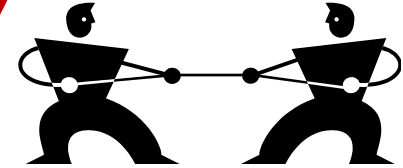
Henry Moseley X-ray Imaging
Facility,
BP International Centre for
Advanced Materials,
University of Manchester
& Research Complex at Harwell

& Bart Winiarski & Tim Burnett

NPL-EPSCRC Fellow & FEI
Research Fellows, University
of Manchester



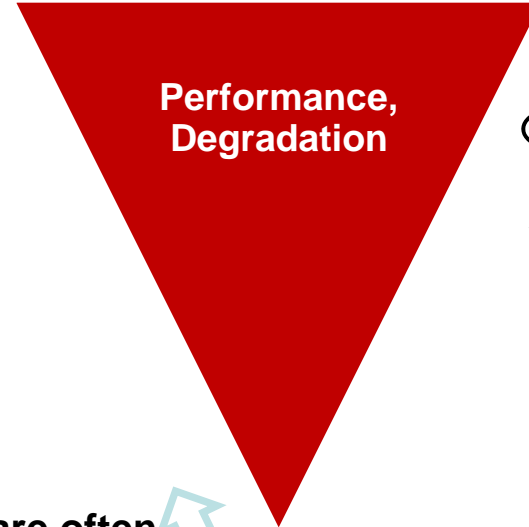
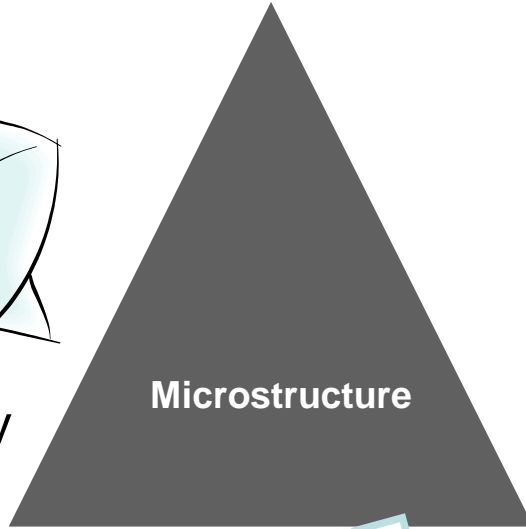
Materials Design Challenge



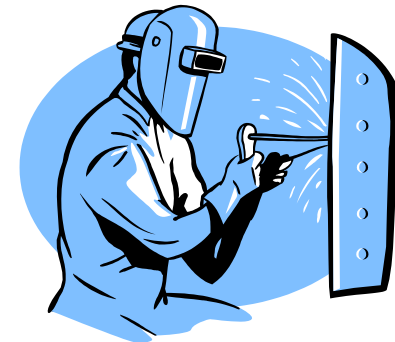
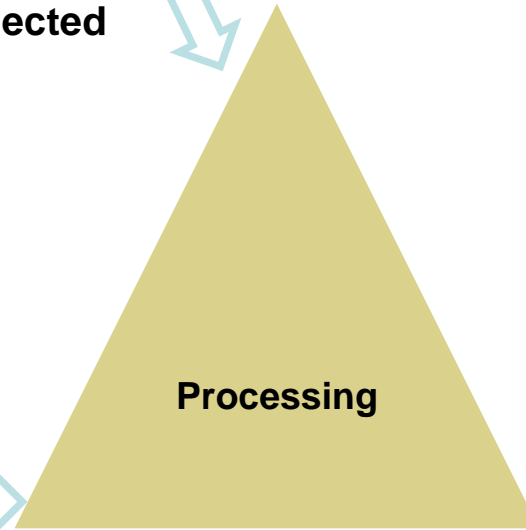
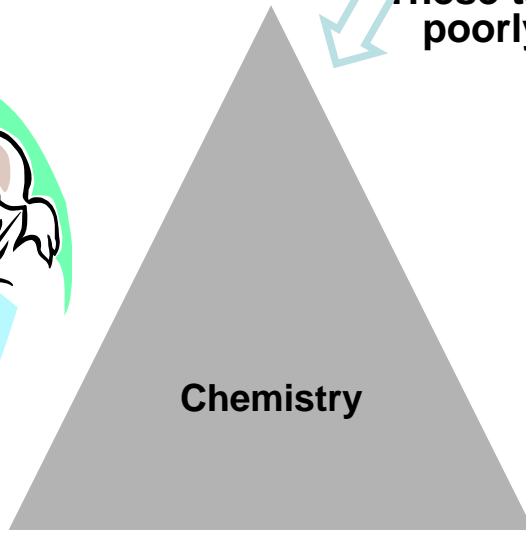
Materials testing lab



Microscopy lab



Chemistry lab



Processing lab

These tasks are often poorly connected



Materials Science Challenge

To design better high performance materials we need to:

- Identify the critical length and time scales
- Bring multimodal information to bear on RoI
- Spatially correlate information at different scales



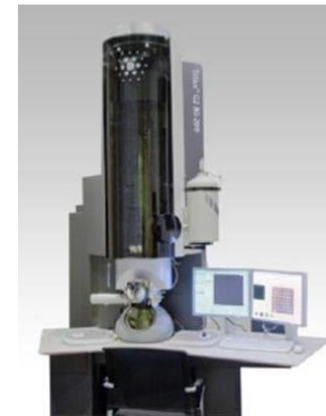
**Optical
Microscopy**



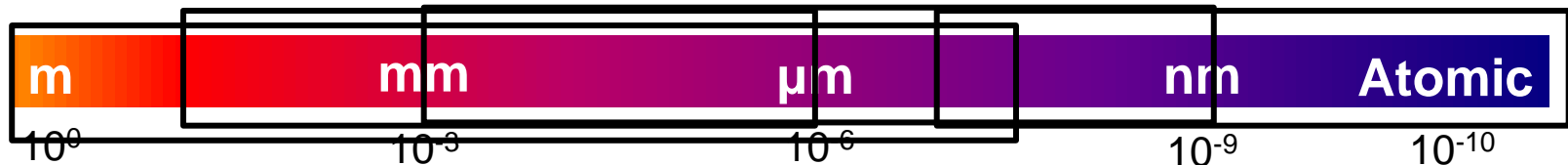
**X-ray
Tomography**



SEM

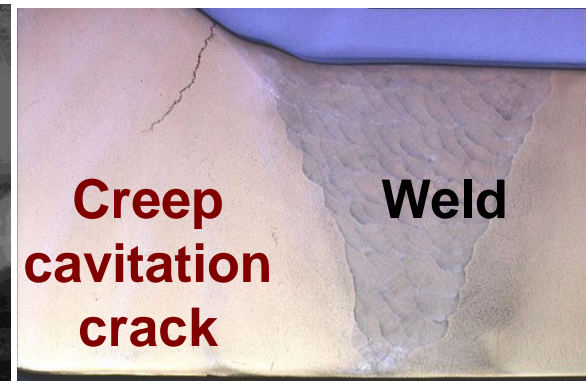


S/TEM



Consider degradation by creep cavitation e.g. boiler spine in a nuclear reactor

- Stainless steel component
- Combination of high temperature and residual stress local to a weld
- Creep cavitation cracking can be life limiting

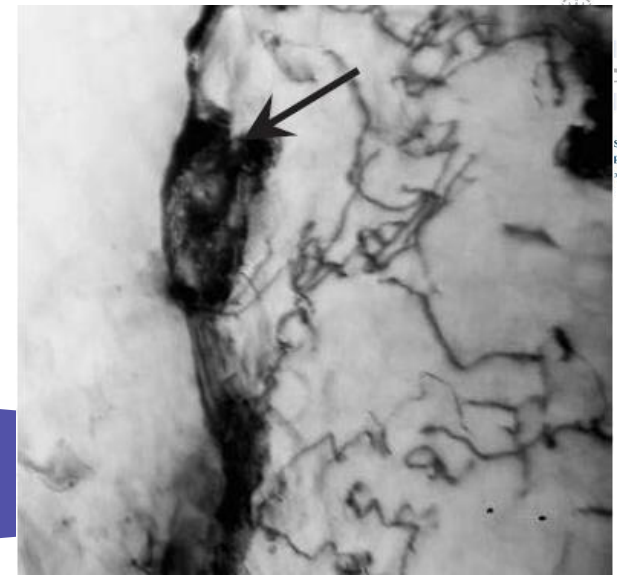


Creep starts at the atomic scale

GB segregation

Point defects

Dislocations



Nanometer

10^{-9}

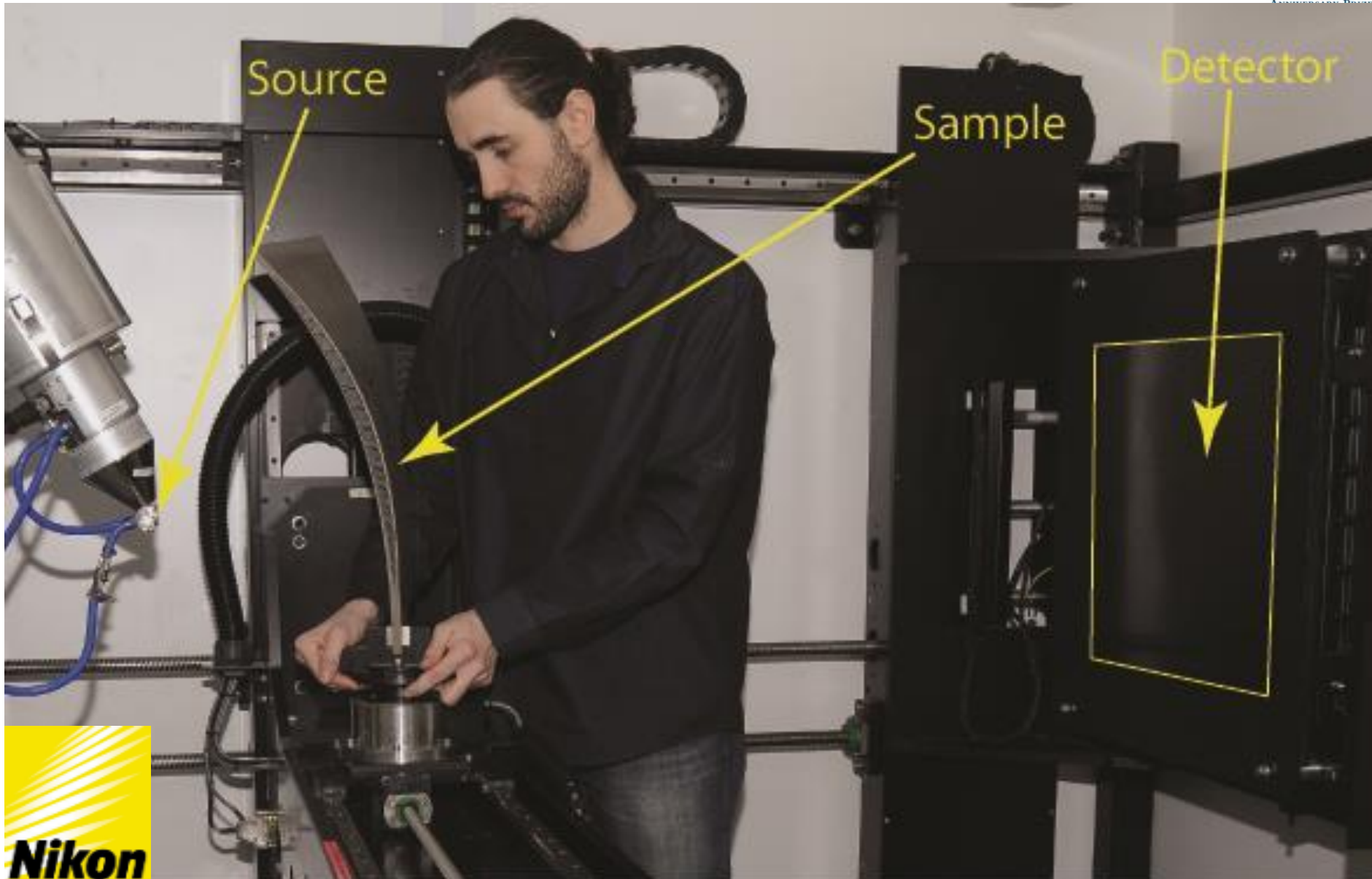
Atomic

10^{-10}

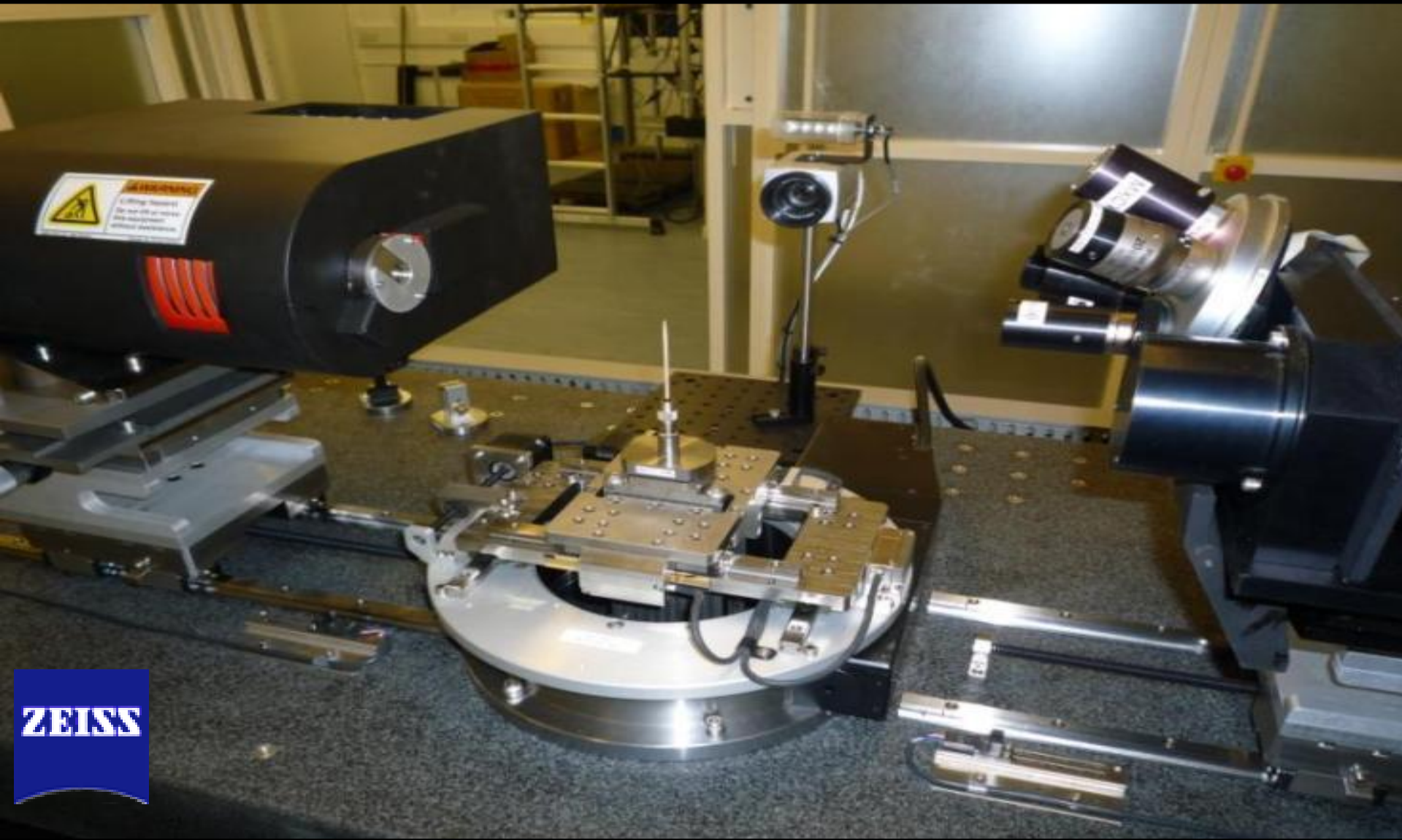
TEM



Large scale imaging

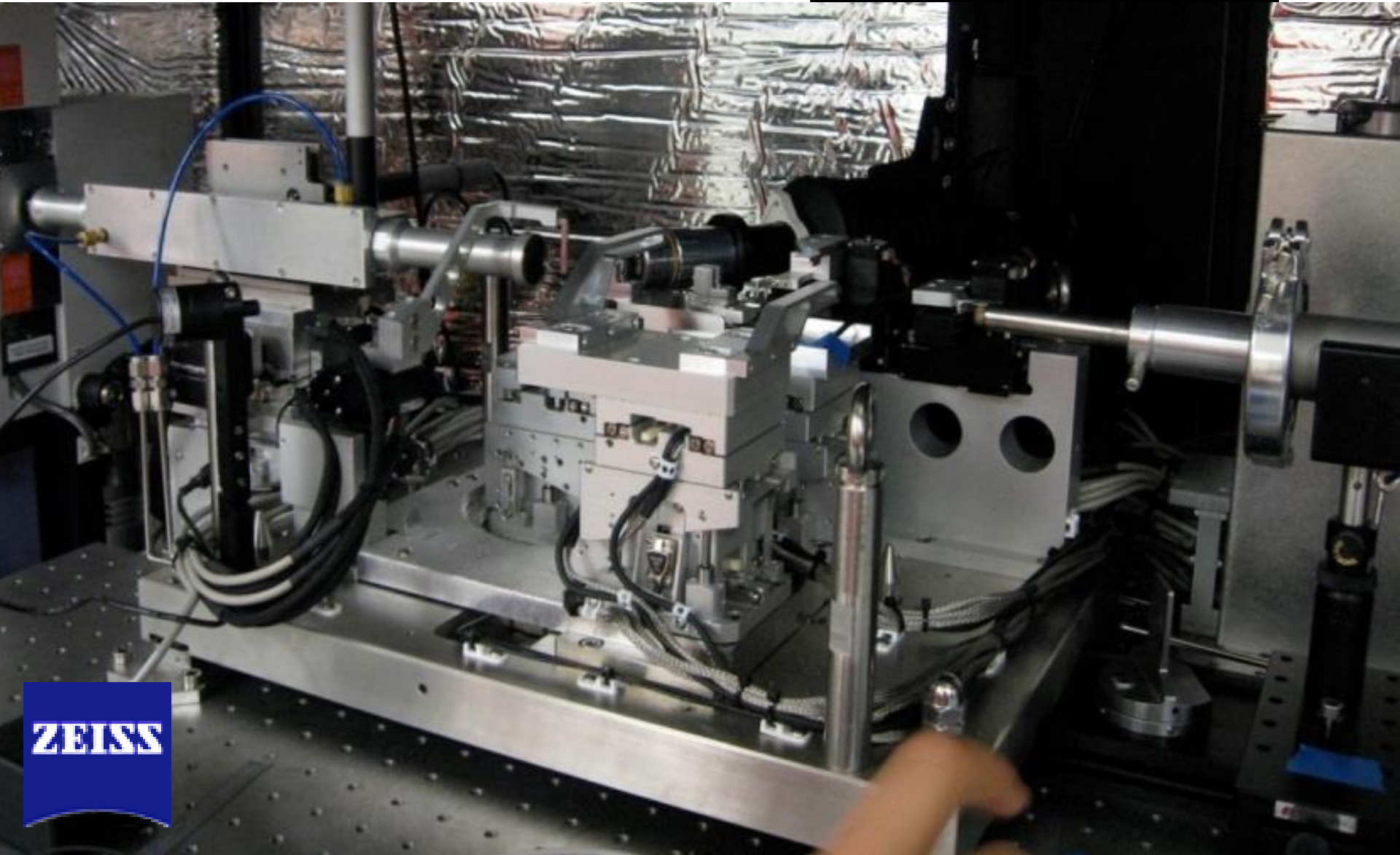


Micron resolution lab. x-ray imaging

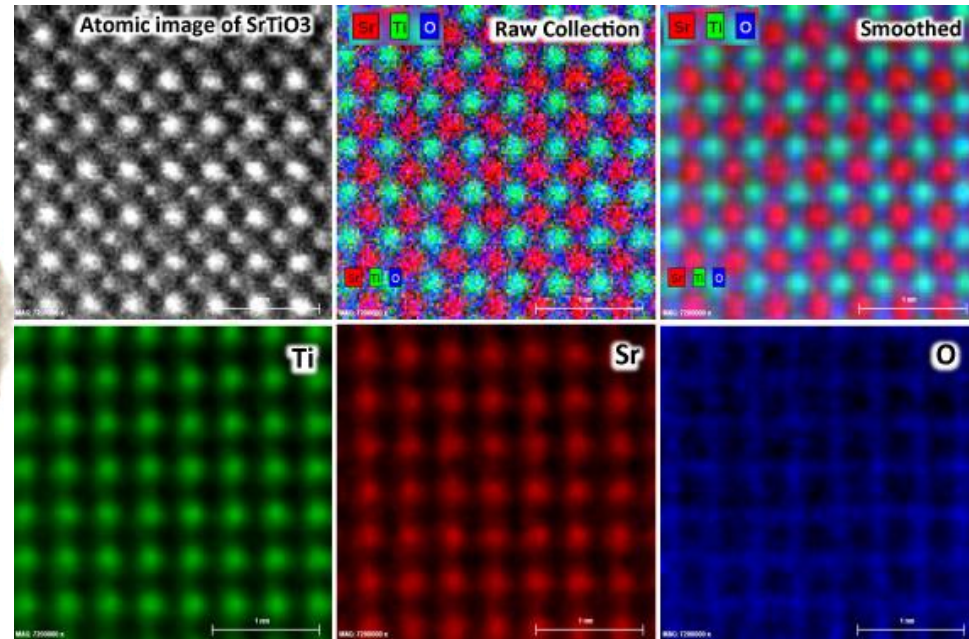
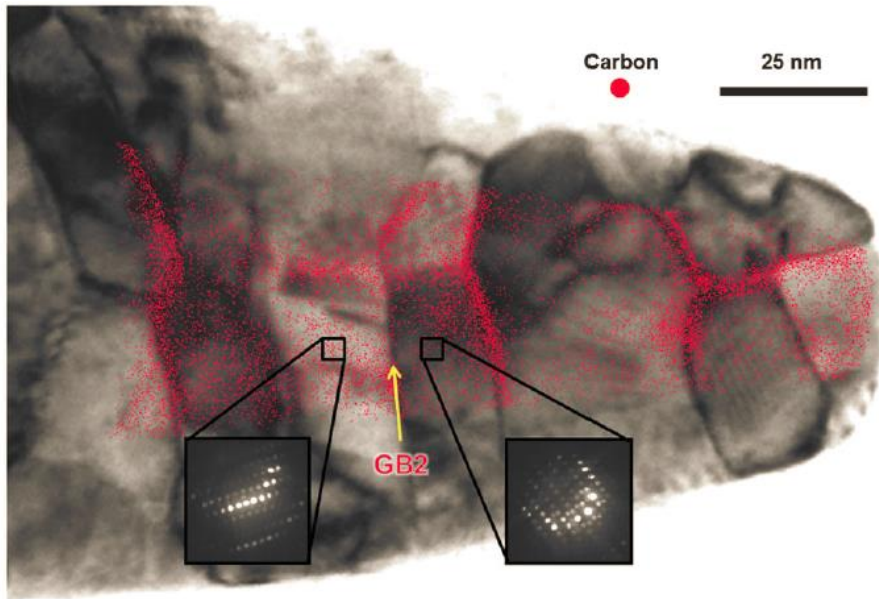


ZEISS

Nanoscale lab. x-ray imaging

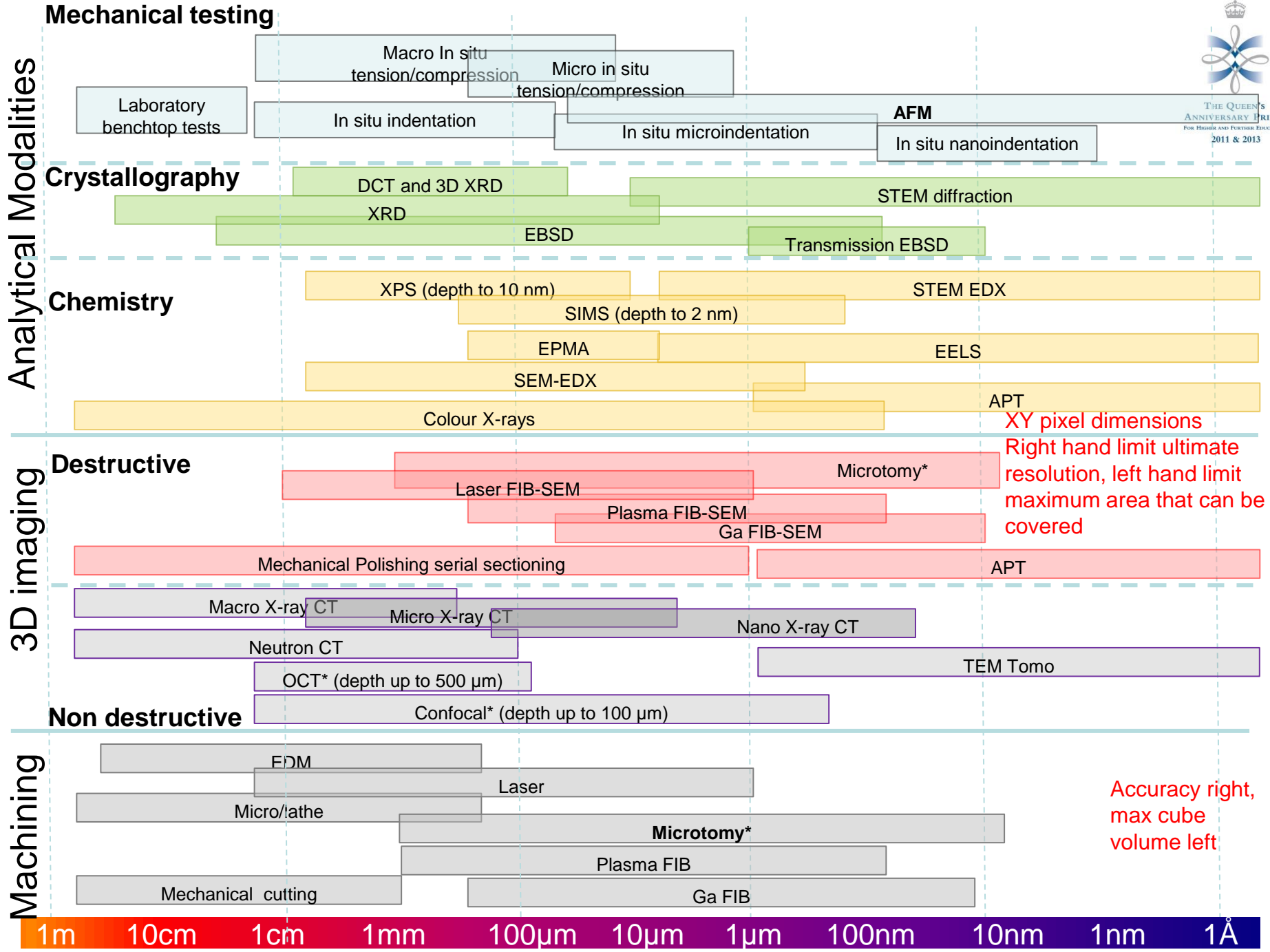


ZEISS



Overlay 3D atom probe map and STEM image of pearlitic steel: GB2, ($\Sigma 3$ coherent twin) shows much lower C segregation than average grain boundary [Herbig, Raabe et al PRL 2014]

Atomic resolution elemental map of SrTiO_3 crystal by Super X EDS on Titan 80-300 Aberration Corrected STEM [NC State Univ]



XY pixel dimensions
Right hand limit ultimate resolution, left hand limit maximum area that can be covered

Accuracy right, max cube volume left



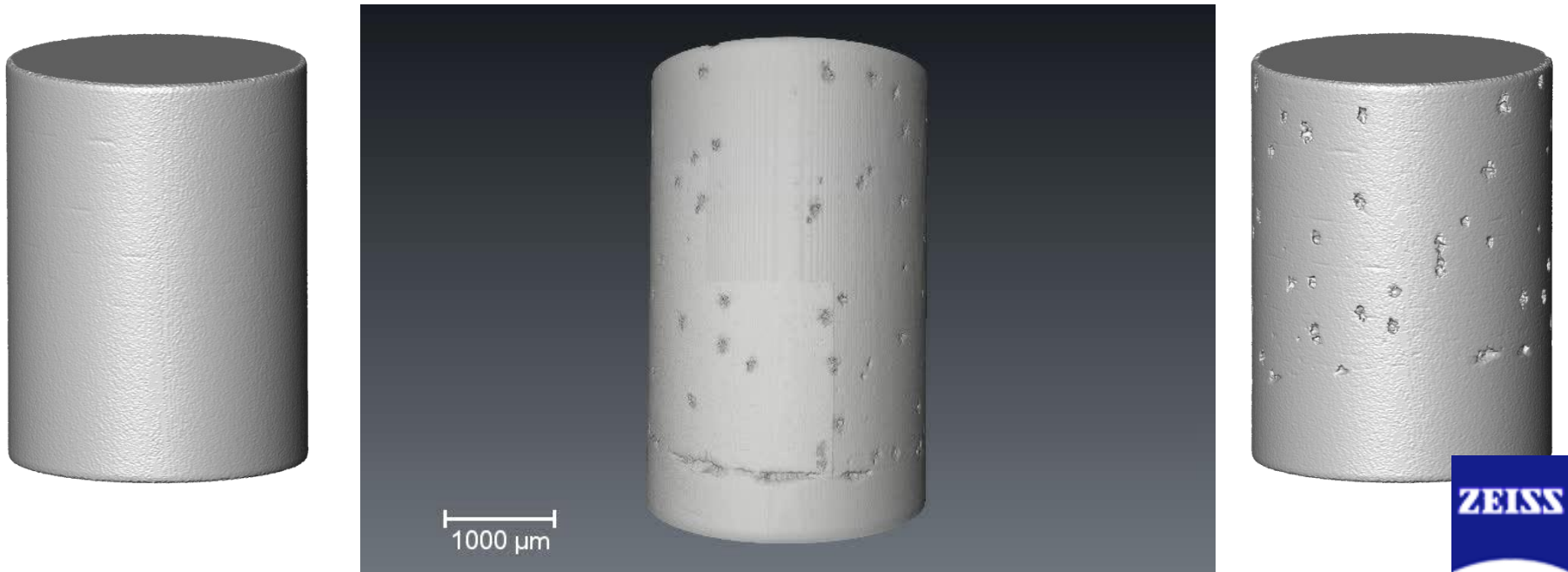
To see the value of a correlative
multiscale framework lets consider
pitting corrosion of a stainless
steel wire

Connecting timescales: Macroscale X-ray CT

Sample immersed in Chloride Solution and polarized

- Time lapse images show nucleation and growth of corrosion pits
- Identification of the fastest or slowest growing pits

But we need to better characterize the pit morphology....

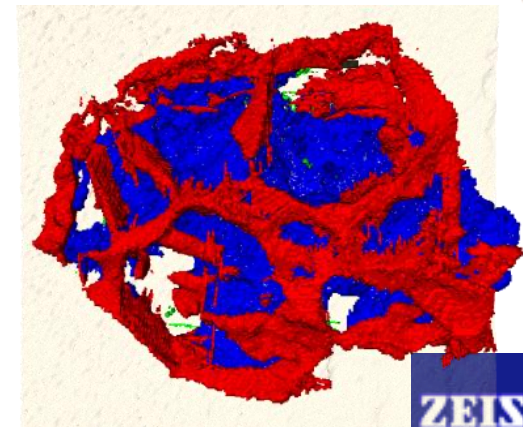
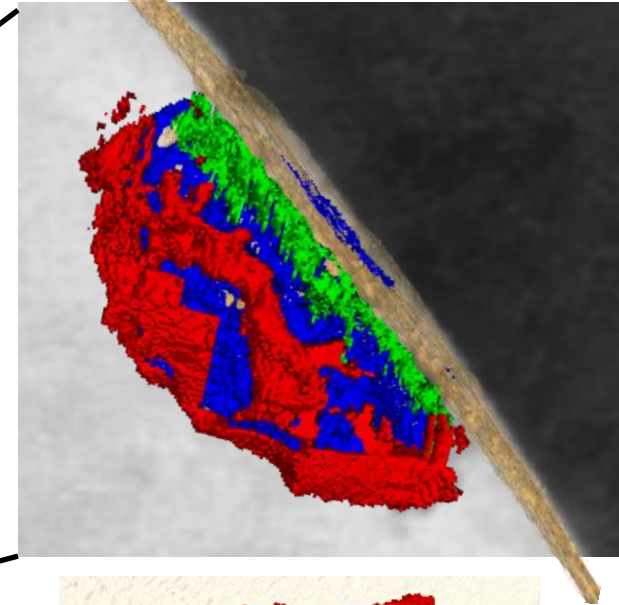
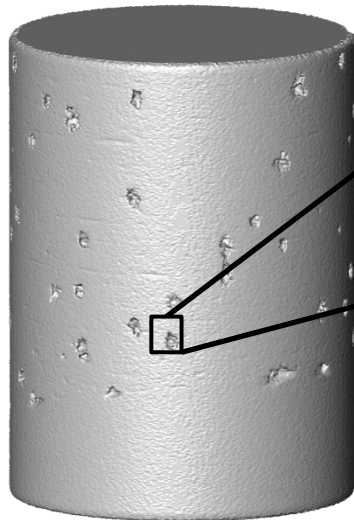


Connecting Scales: high-resolution X-ray CT

Use macroscale X-ray CT as a 3D map to find ROI for microscale X-ray CT

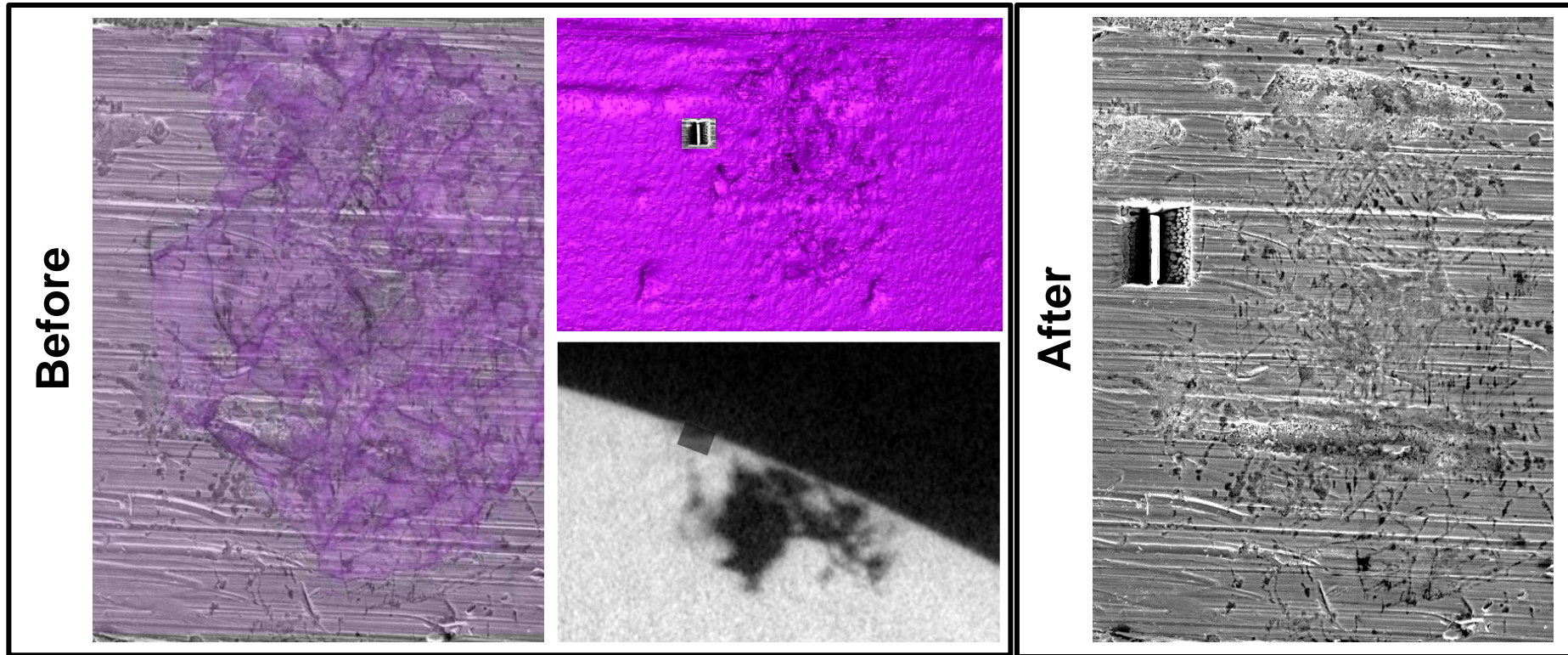
- We can now see the detailed morphology of the corrosion pit, revealing a network of 'intergranular' corrosion surrounding the pit

We now need to explore the microstructure around the pit in more detail....



Correlative Tomography: Linking X-ray CT to SEM

Manually register the surface as rendered from X-ray CT to the SEM image to locate periphery of pit obscured by a lacy cover:

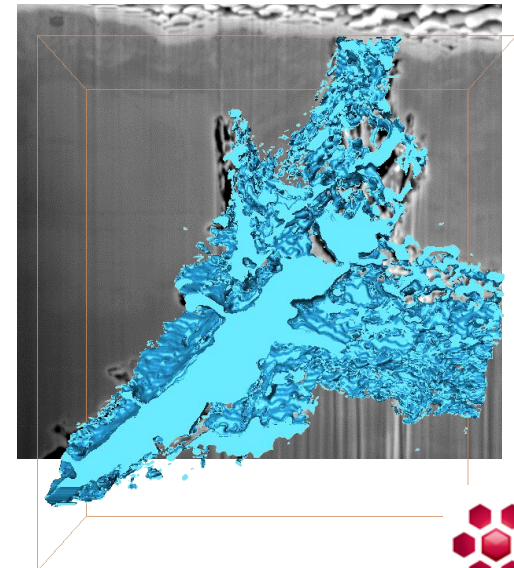
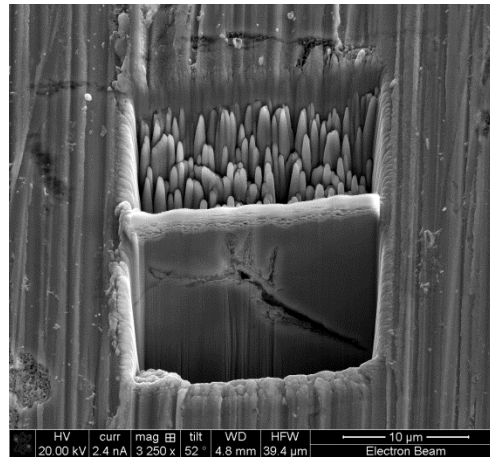
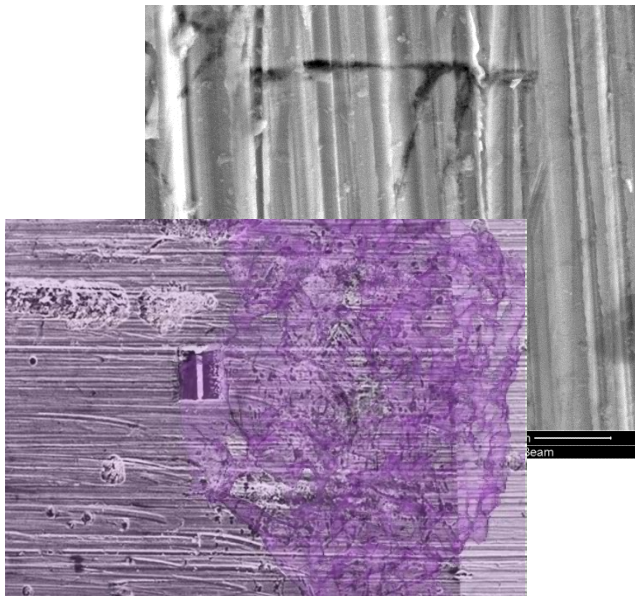


Correlative Tomography: FIB-SEM serial sectioning

3D analysis at the nanoscale using Slice and View

- Destructive but very high resolution and SEM imaging reveals contrast from grain boundaries
- Characterize the shape, extent and direction of the corrosion fronts

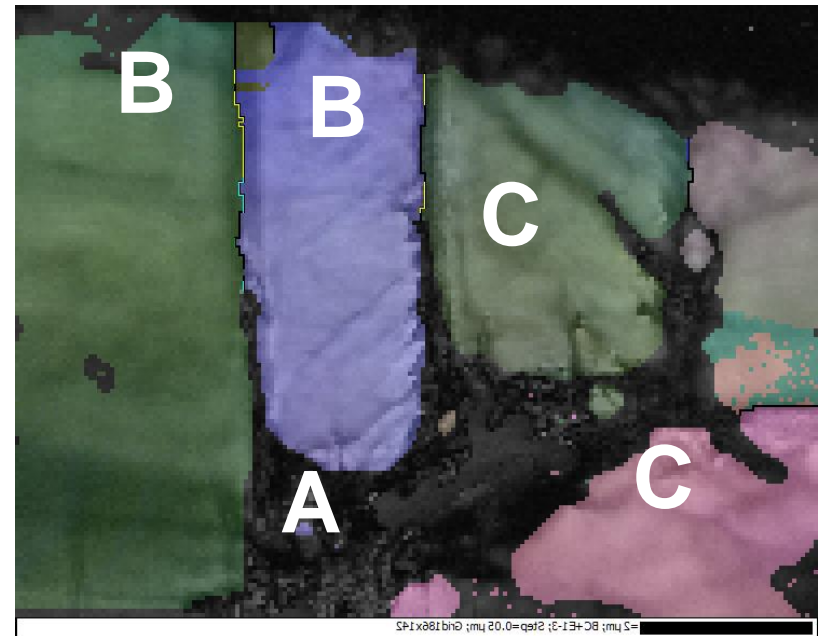
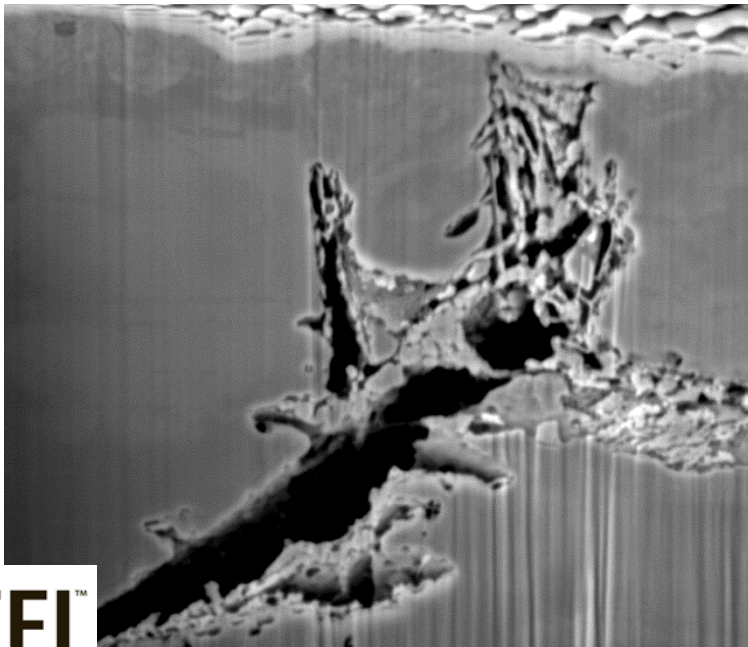
But we need to understand the crystallography to identify the corrosion fronts....



Electron backscatter diffraction has enabled analysis of the crystallography around the corrosion fronts

- We have identified high angle grain boundaries (A), coincidence site lattice (CSL)(B) and slip bands (C)
- The structural disorder of each of these boundaries appears related to the degree of corrosion

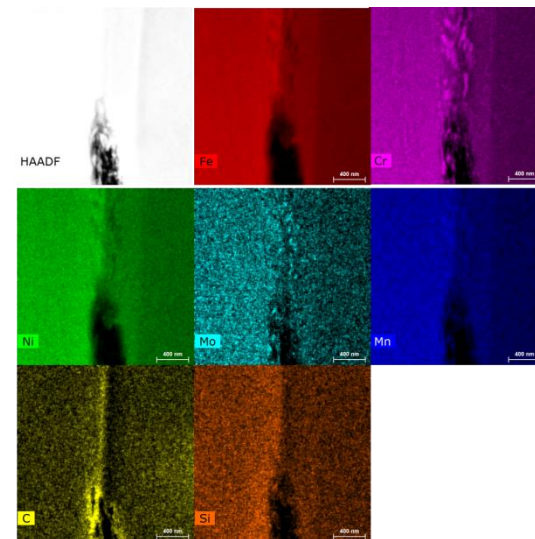
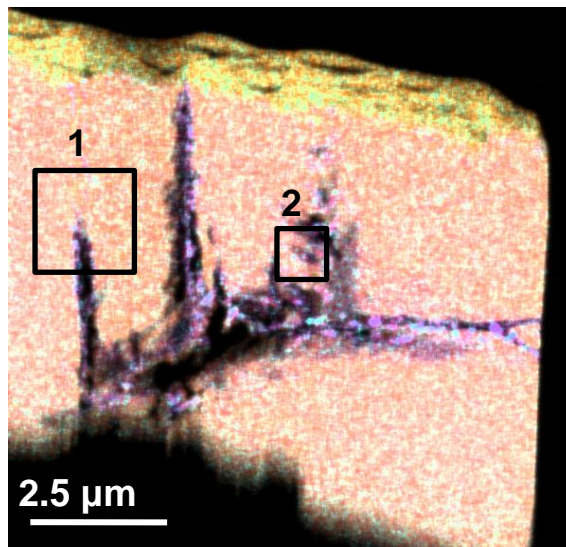
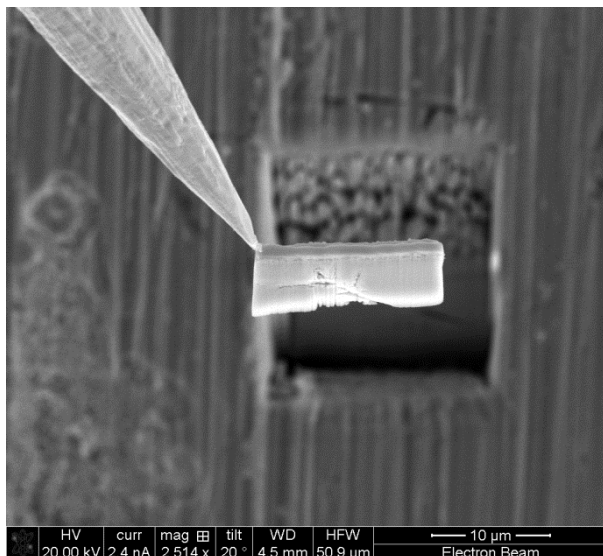
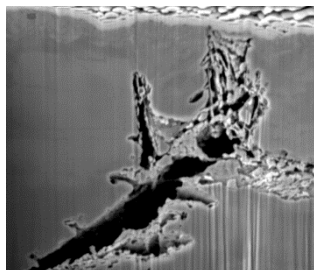
But we need to understand the role of the materials chemistry....



Connecting modalities: Nanoscale Chemical Analysis

Chemical Mapping with Titan ChemiSTEM-EDS

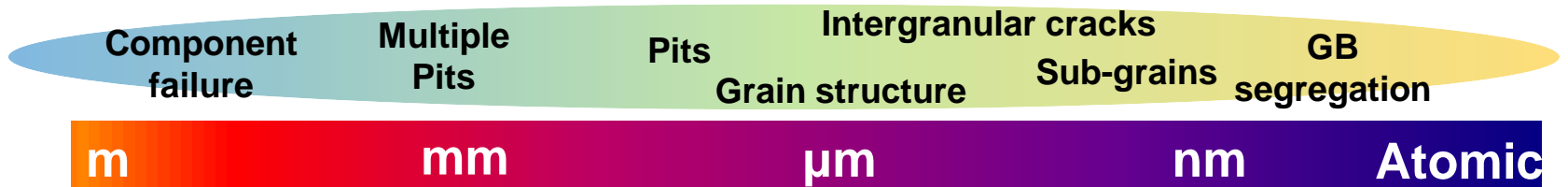
- GB and CSL are associated with chemical segregation
- Slip bands have not yet shown any chemical segregation

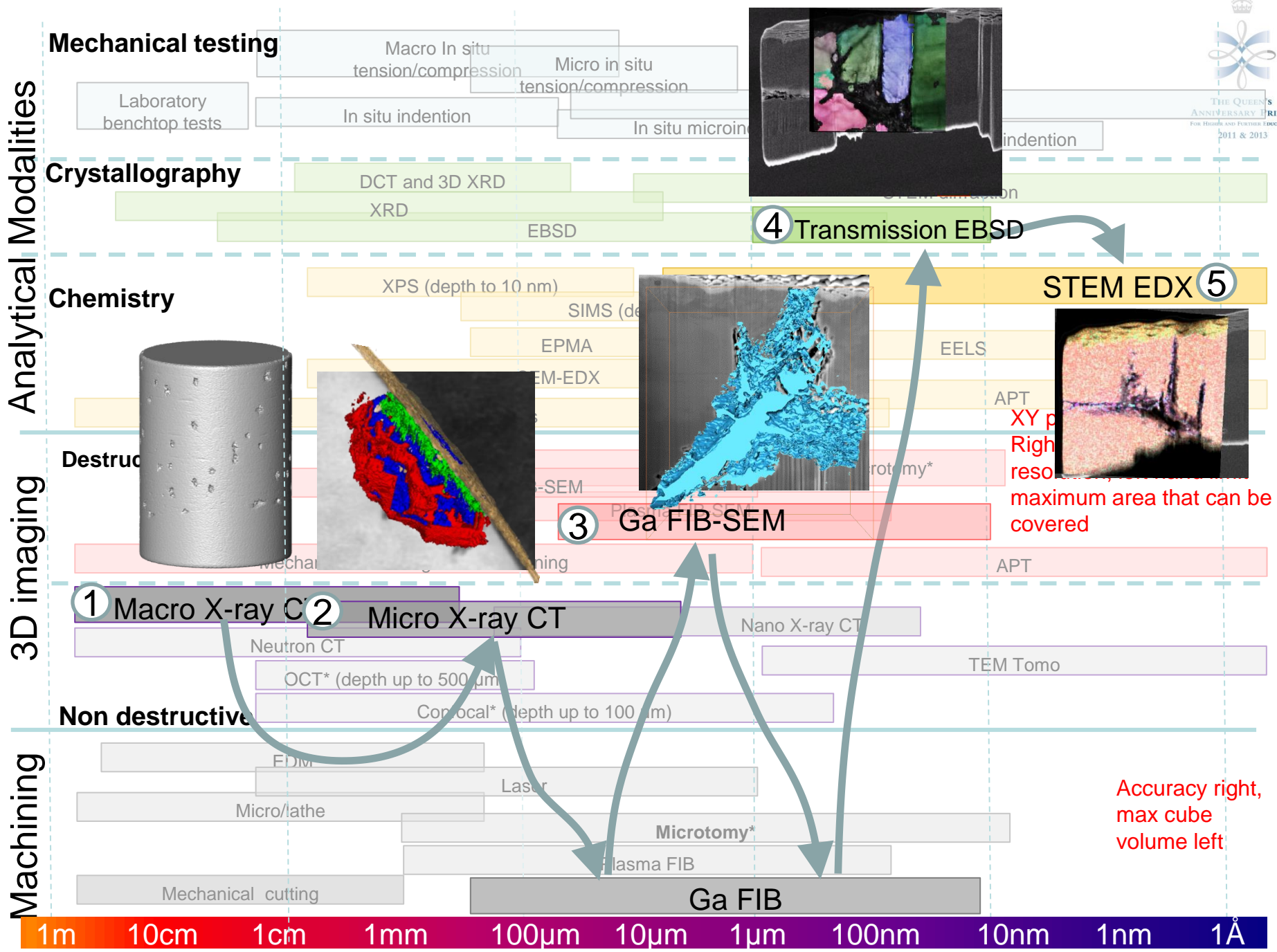


Correlative Tomography

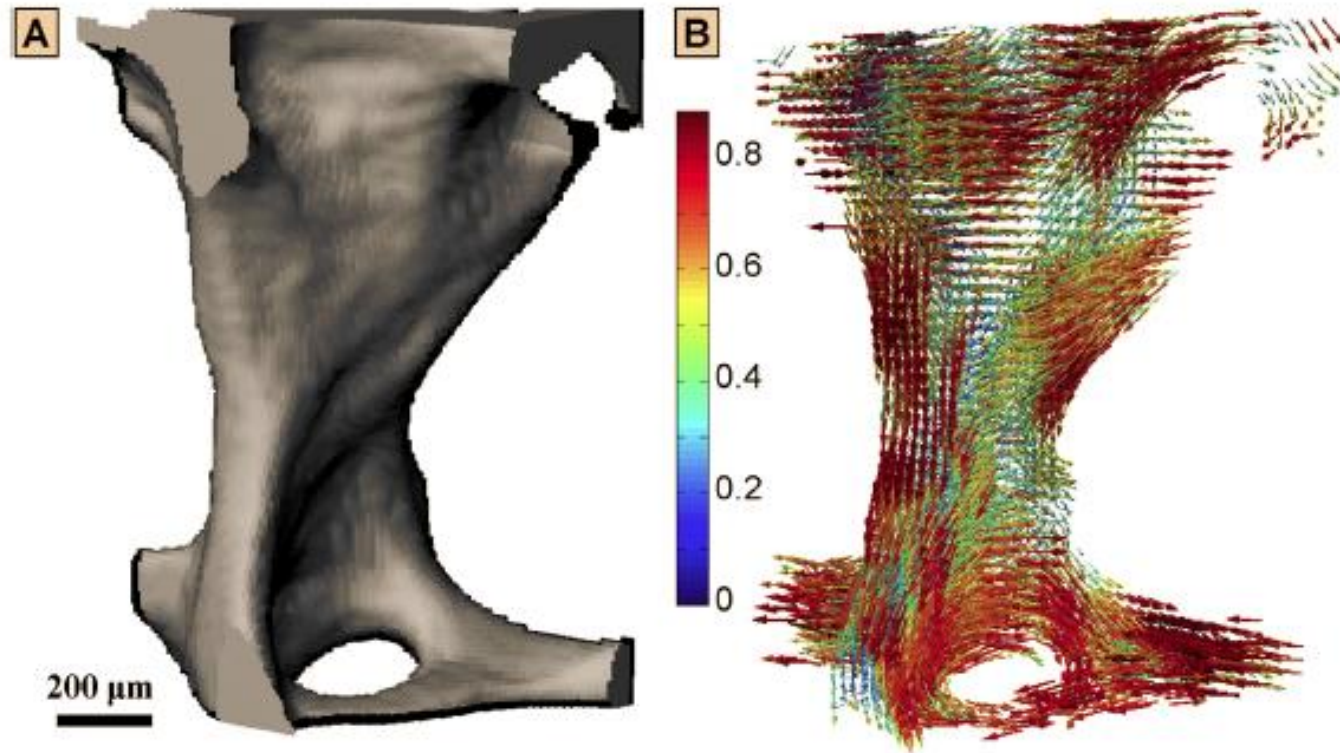


Macroscale X-ray CT (3.4 μm voxel size)





We now have advanced tools to map microstructures across the scales:

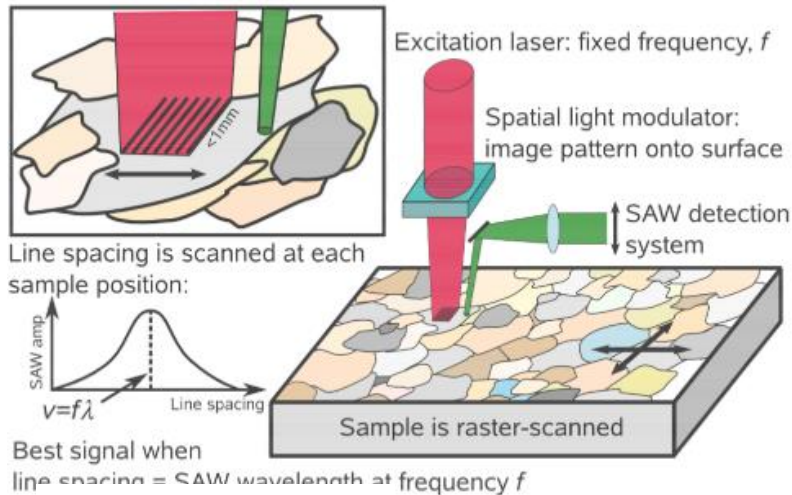


3D map of crystalline orientation in bone trabecula [Georgiadis et al Bone 2014]

Challenge is to correlate these to mechanical properties across the scales

Mechanical characterisation at the millimetre (polycrystal) scale.....

Mapping elastic properties - Spatially resolved acoustic spectroscopy (SRAS)

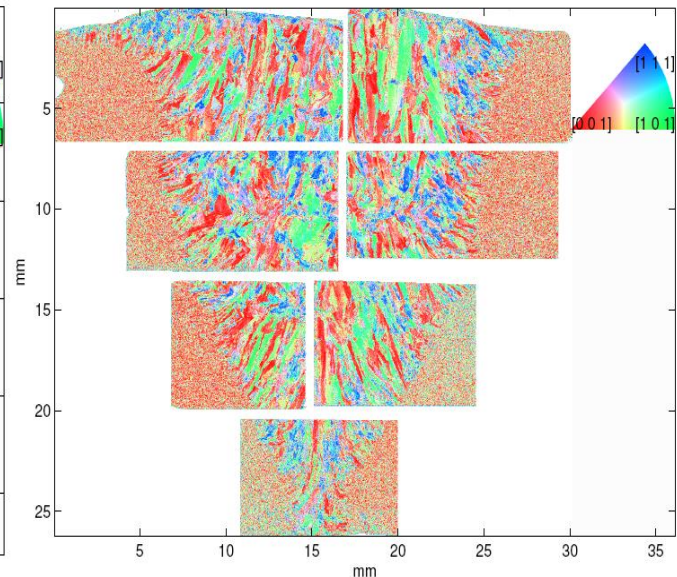
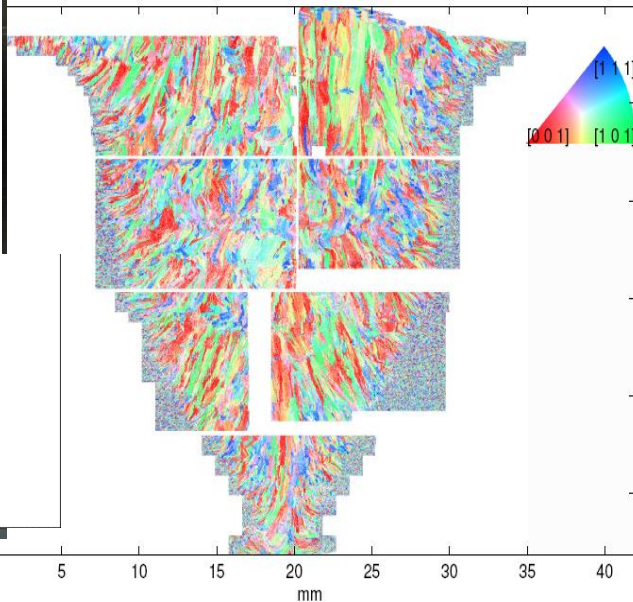
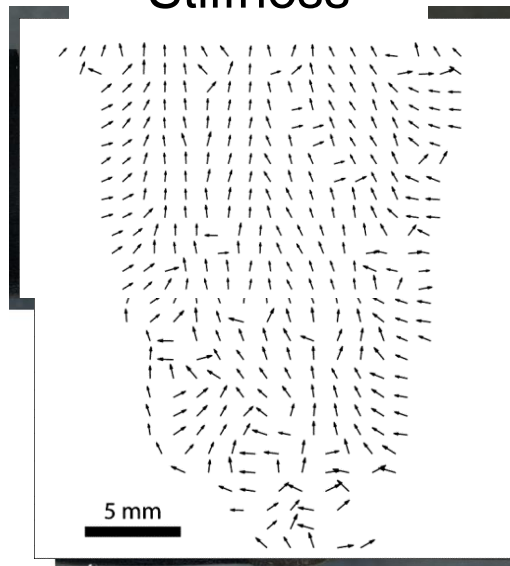


- With Steve Sharples (Nottingham), Lowe (Imperial College)

Stiffness

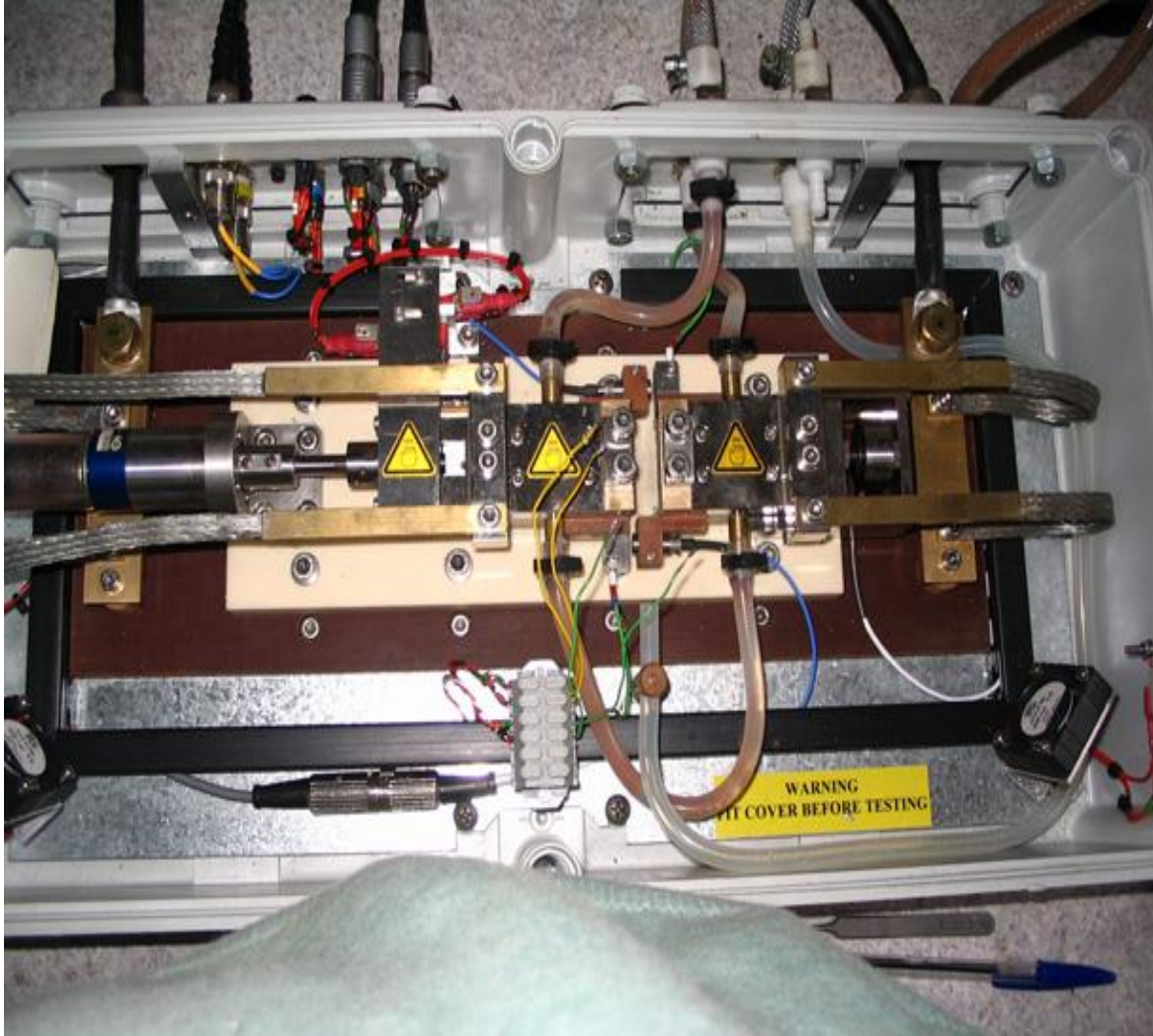
(EBSD:UoM)

(SRAS:Nott)



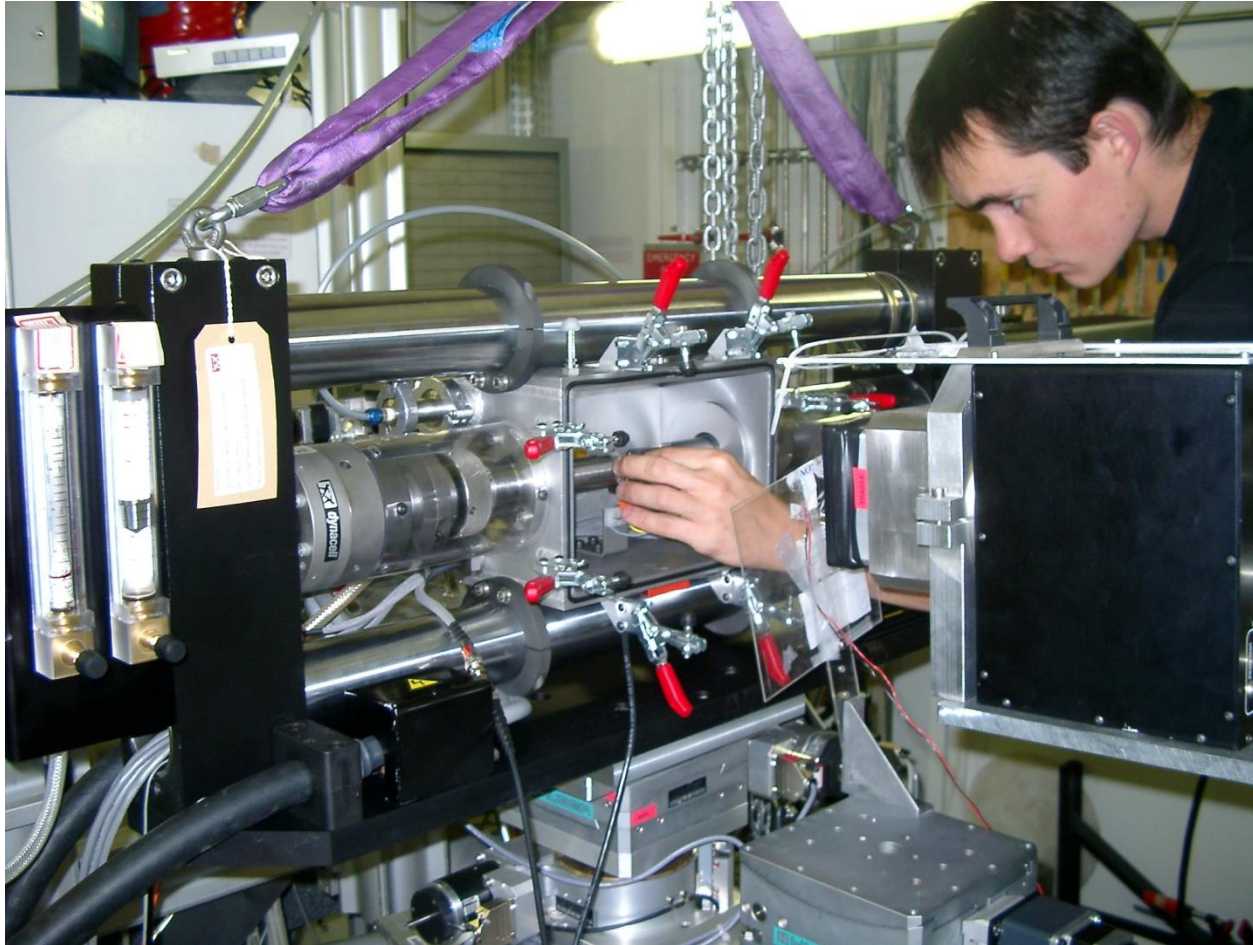
(SS308 TIG weld)

Mapping plastic properties: The ETMT



- Originally developed by Brian Roebuck et al. NPL

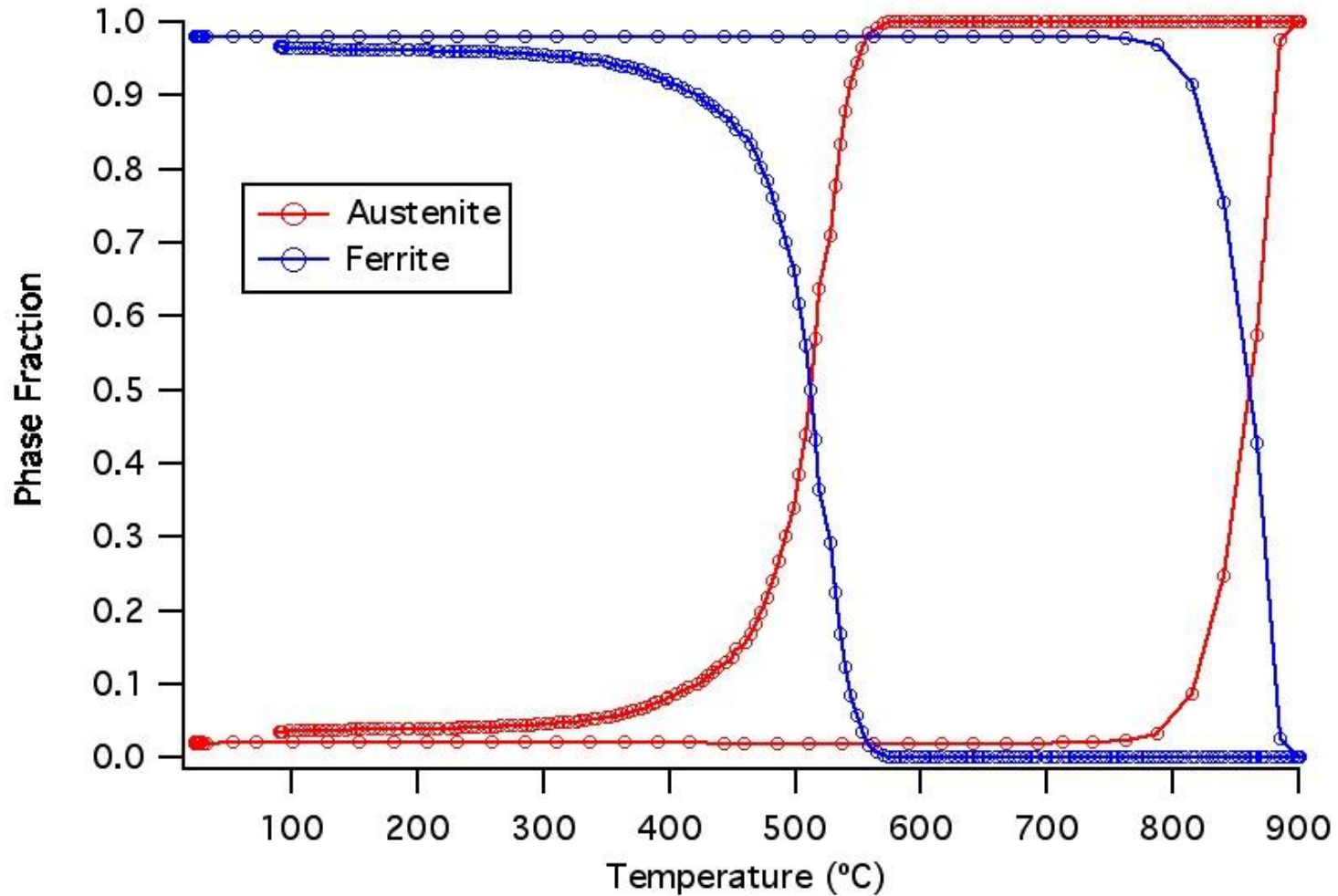
In situ monitoring of smart weld filler during weld cooling



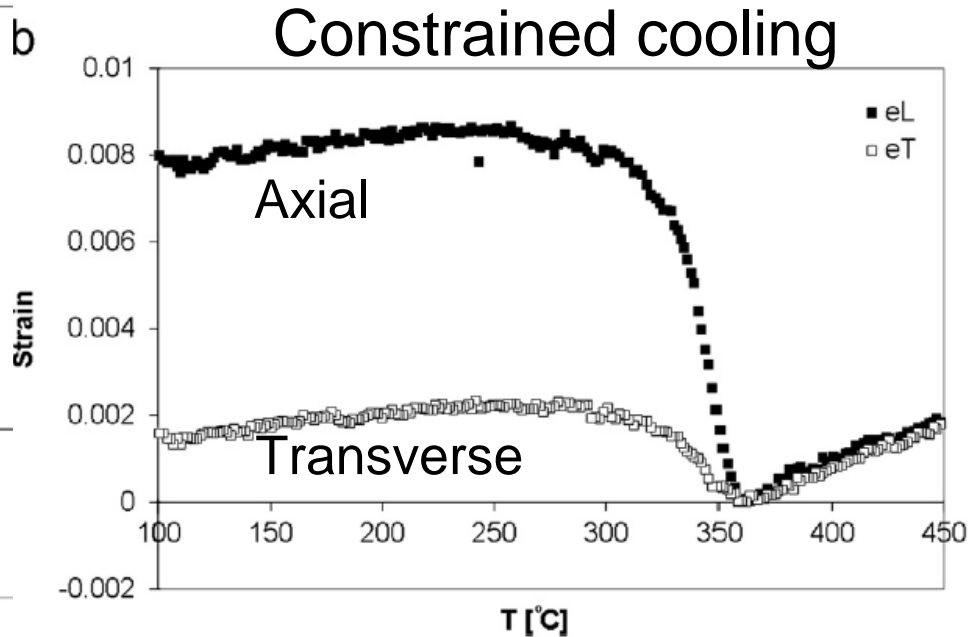
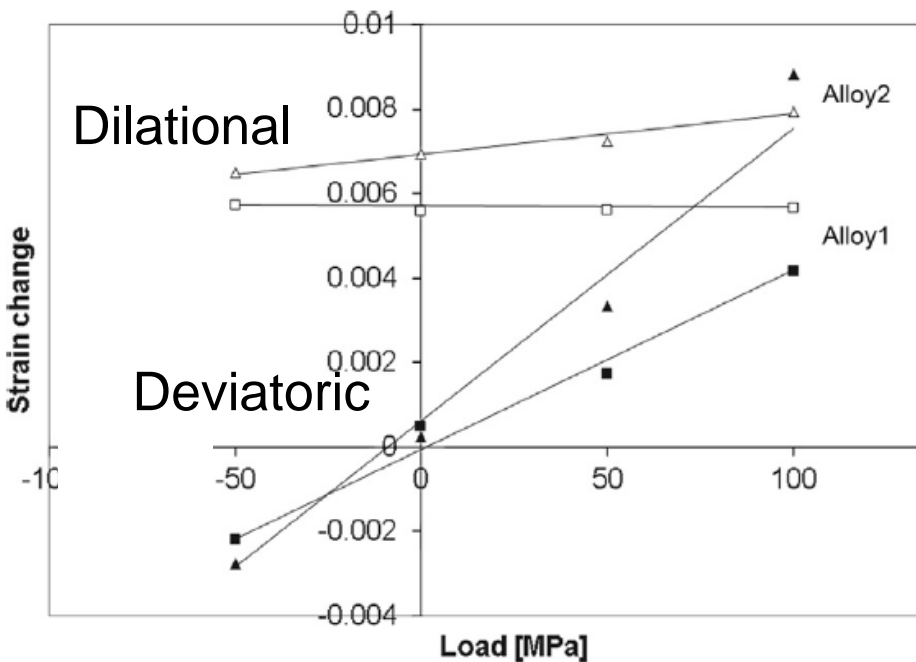
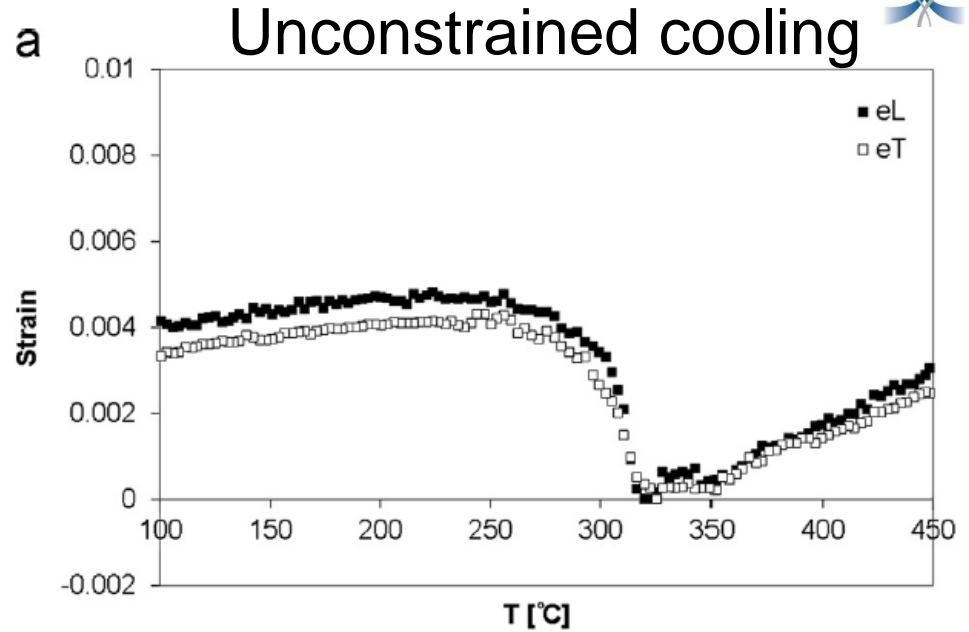
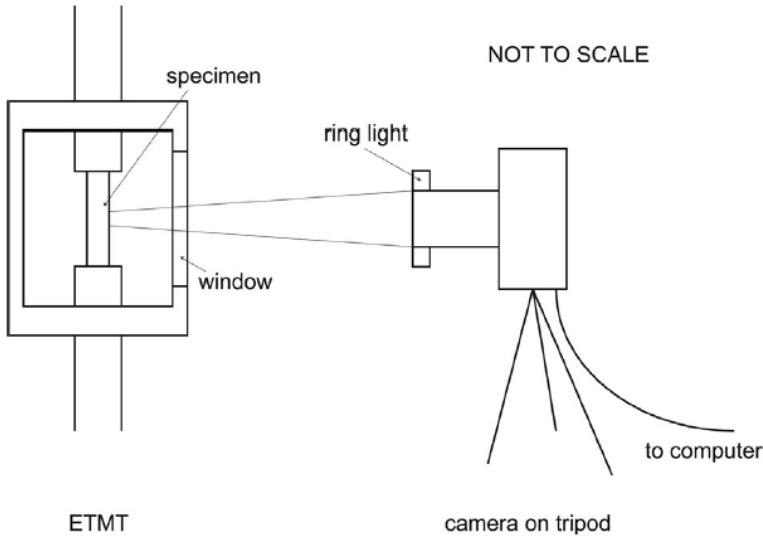
Instron
version of
ETMT

- Experiments conducted at ID11 beamline at the ESRF synchrotron facility

Evolution of phase fractions



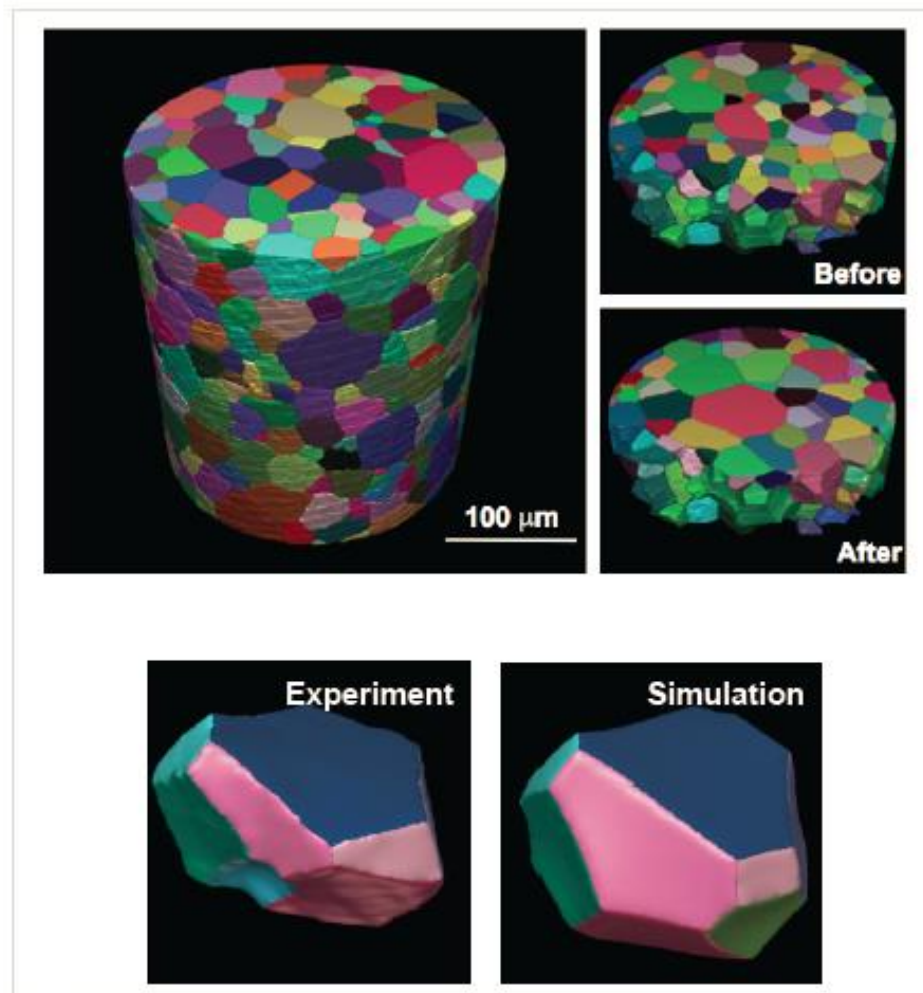
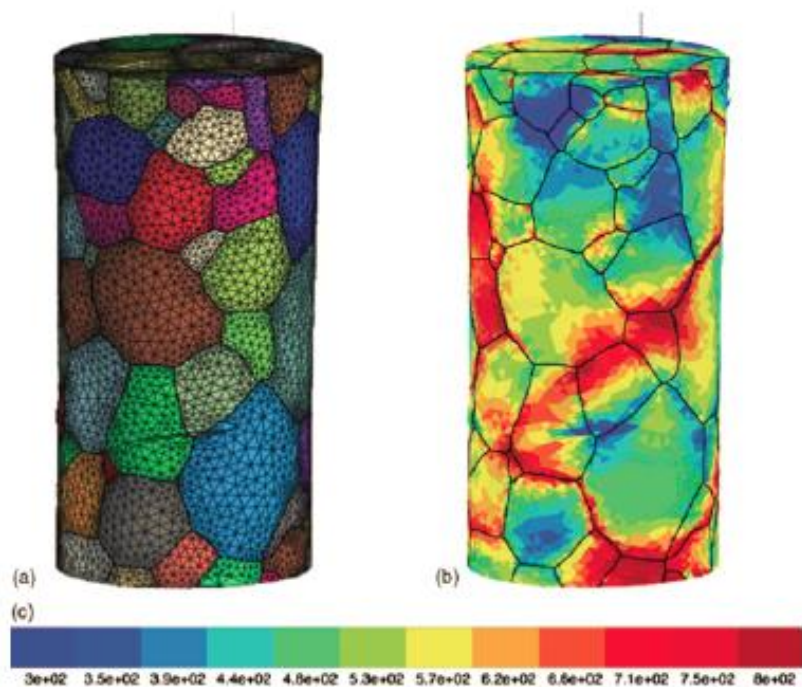
- Full structural (Rietveld) refinement of the diffraction patterns to obtain phase fractions



**Mechanical characterisation at
the tens of micron (grain to grain)
scale.....**

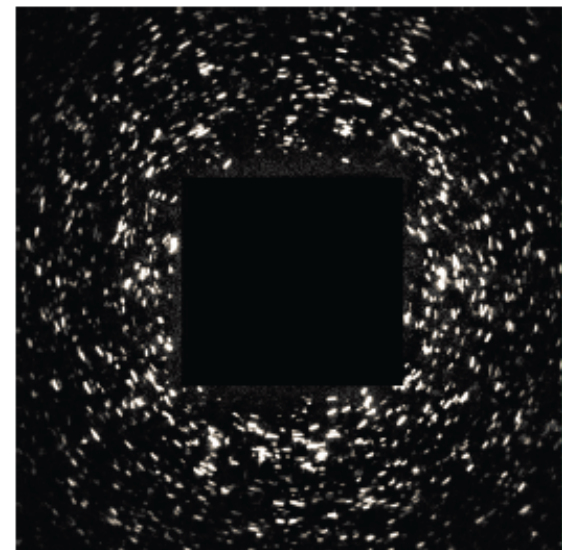
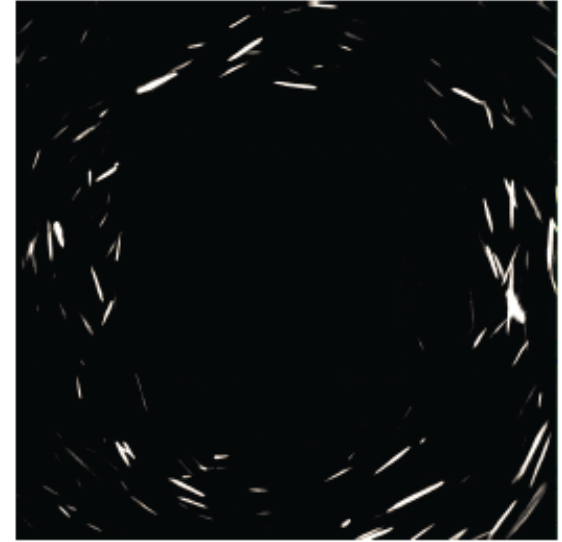
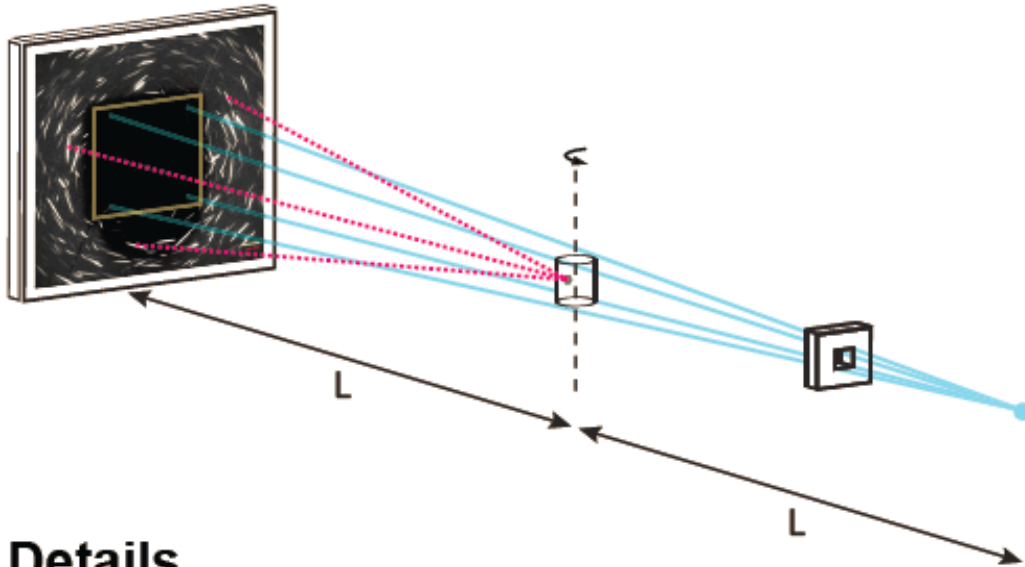
Coupling to 3D simulations

- 3D grain maps are perfectly suited for coupling to 3D computer simulations of microstructure evolution



New lab-based 3D grain mapper (Zeiss-Xnovo-UoM)

Version 0.5 implementation: Laue focusing geometry



Details

- Add-on module to standard Xradia Versa 520 XRM
- Utilizes white divergent X-ray beam
- Utilizes Laue focusing geometry



Laboratory Diffraction Contrast Tomography (DCT): crystallographic information

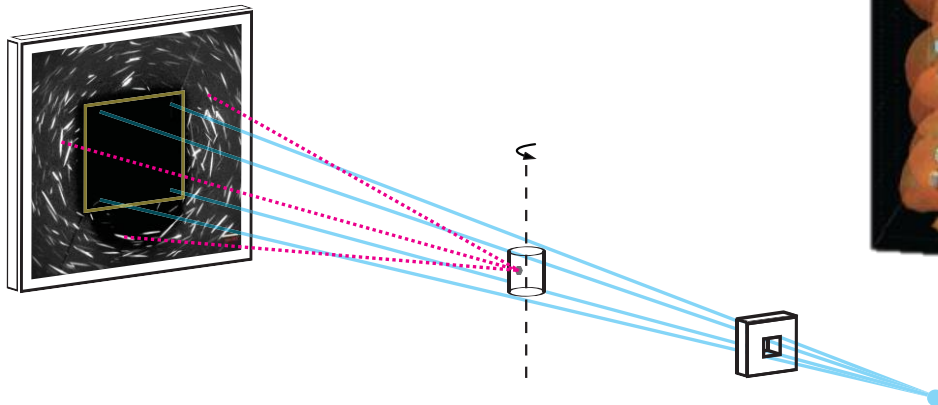
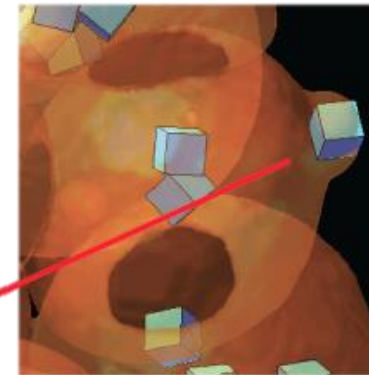
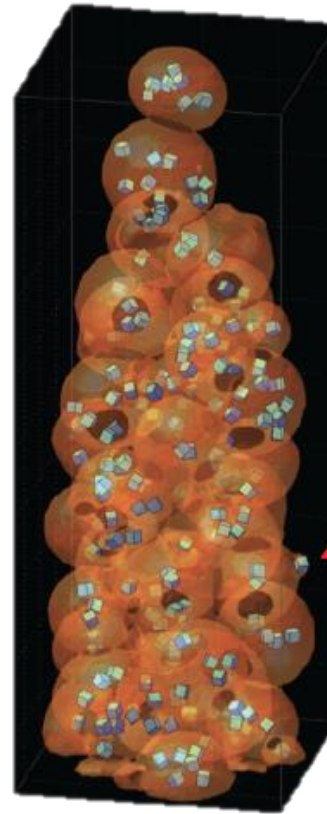
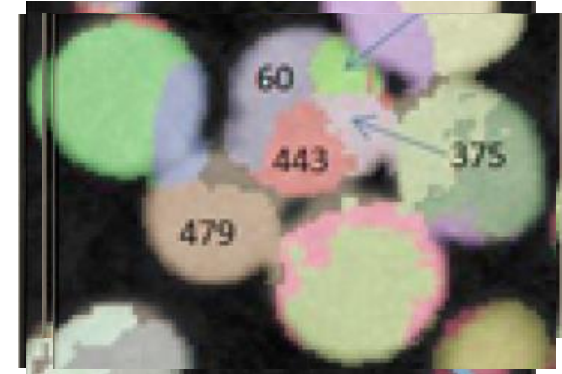
Synchrotron DCT well established

- 3D crystallographic grain maps
- e.g. 3D sintering of Cu particles

Bringing synchrotron technology to the laboratory

- 3D crystallographic information obtained on a laboratory XRM (**ZEISS Xradia 520 Versa**)
- Non-destructive 3D grain mapping in lab.

2 hours



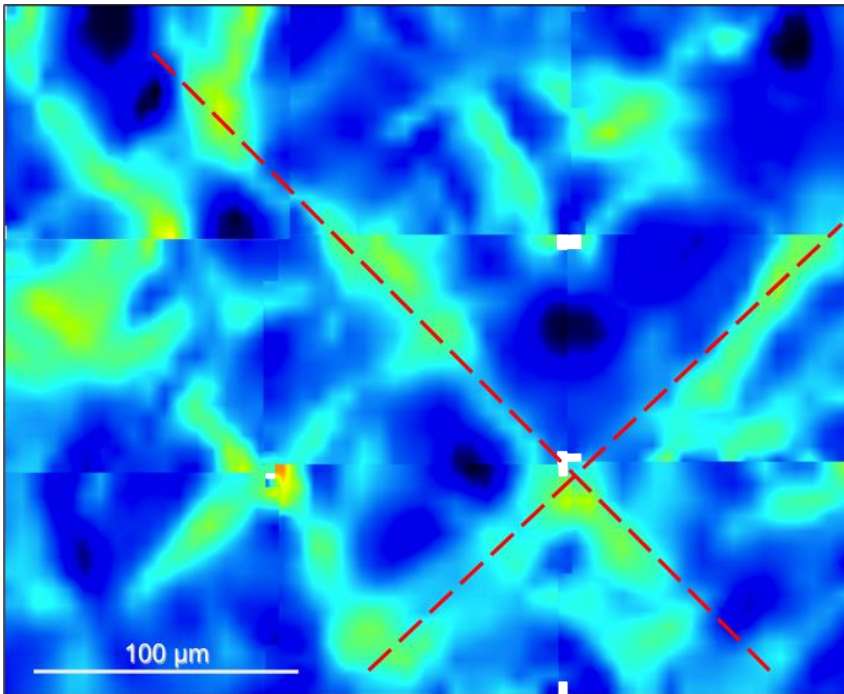
- Electron Back Scatter Diffraction
 - Before deformation:
 - Grain boundaries
 - Grain orientations (slip traces)
 - After deformation
 - Lattice rotations (local misorientation)
 - Low angle grain boundaries
 - Spatial resolution: 0.2 μm
- High Resolution Digital Image Correlation
 - In-plane deformation gradient
 - In-plane strain, rotation and their gradients
 - Spatial resolution: 0.2 μm



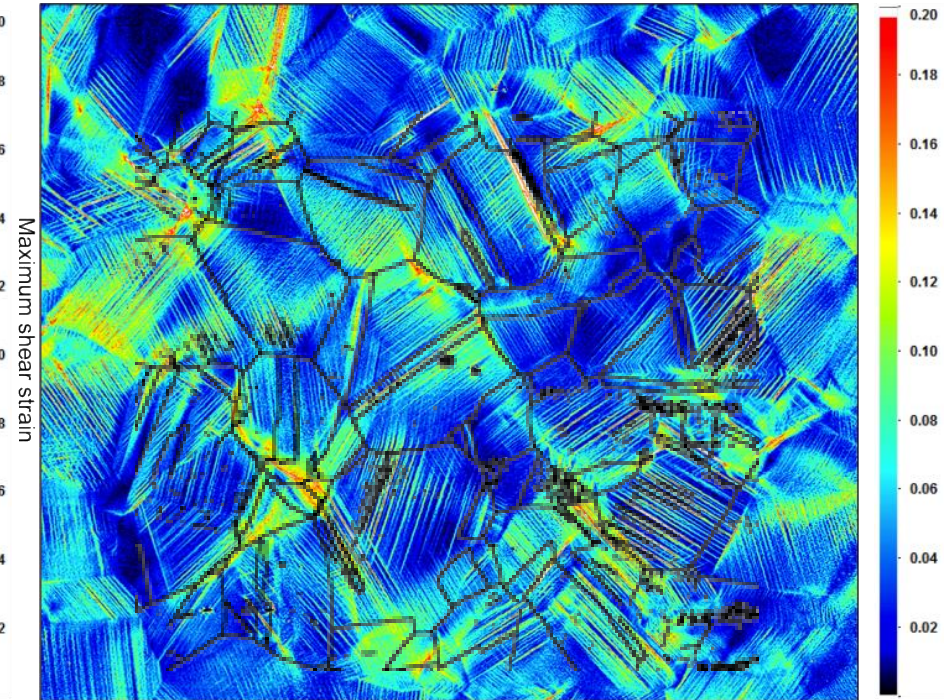
- Sub-micron spatial resolution strain maps

400 VECTORS PER $100 \times 100 \mu\text{m}^2$

200,000 VECTORS PER $100 \times 100 \mu\text{m}^2$



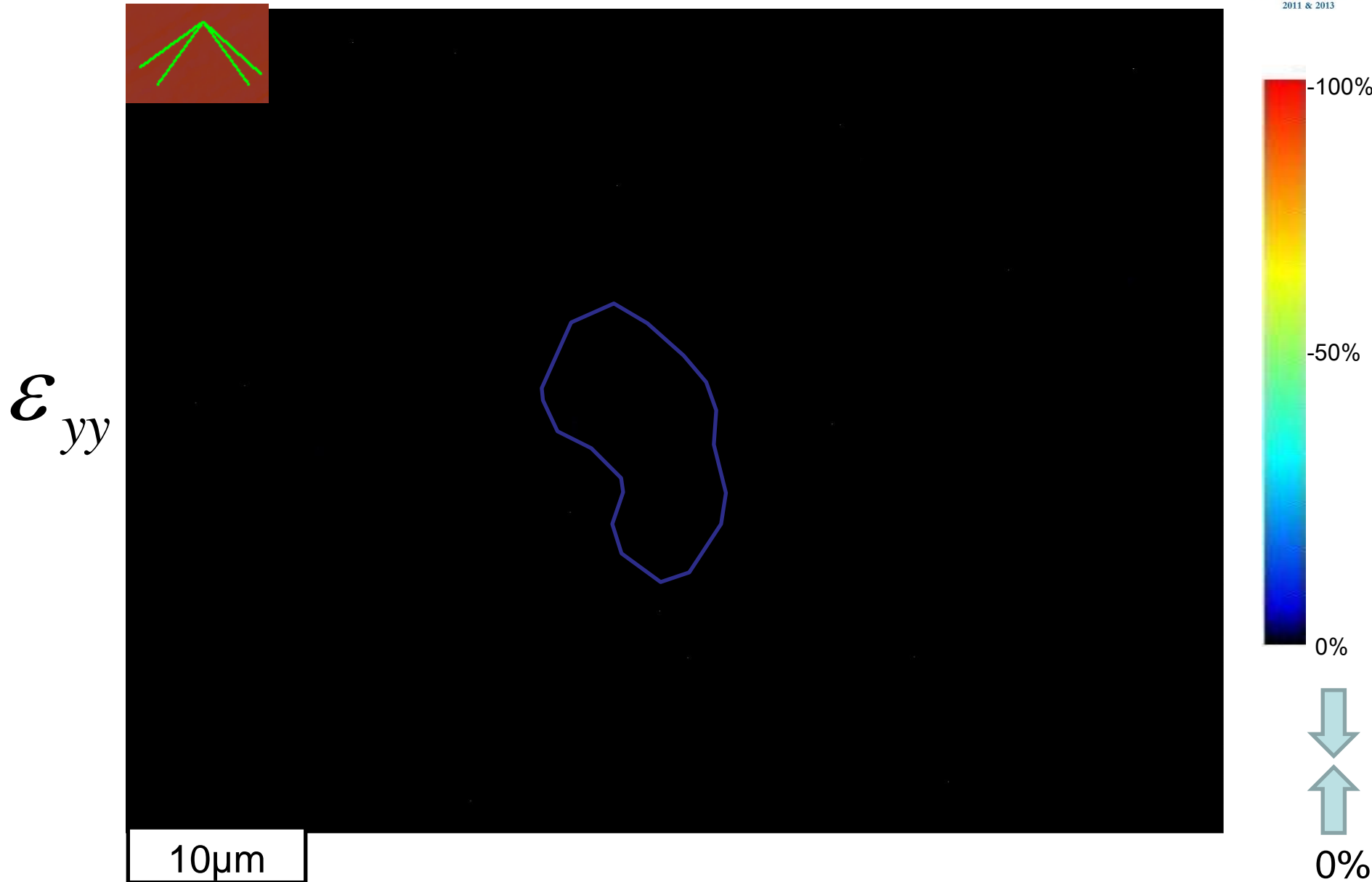
Natural contrast



Gold speckle

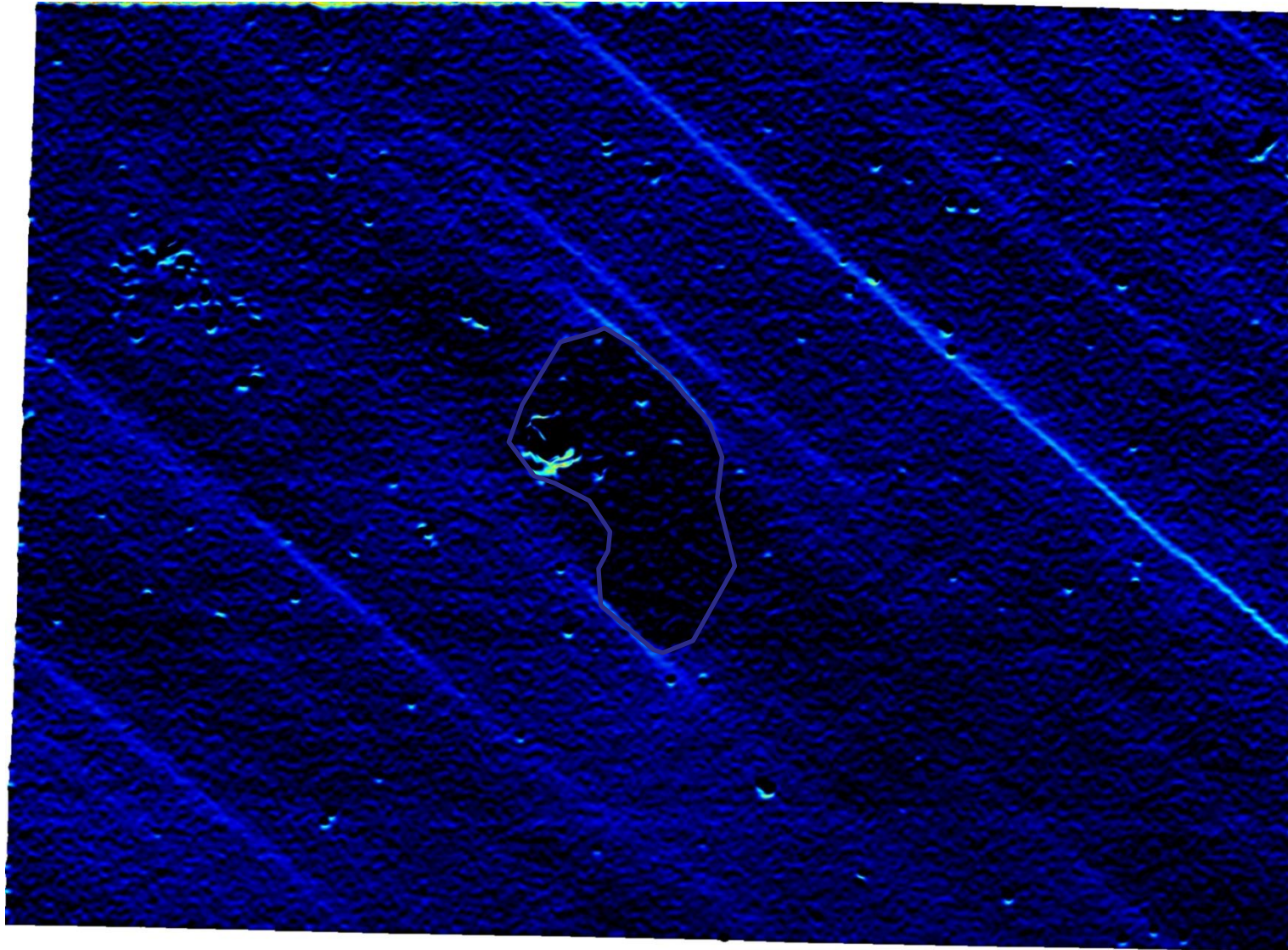
(LAVision DIC)

Al-Si Local strain evolution



Al-Si Local strain evolution

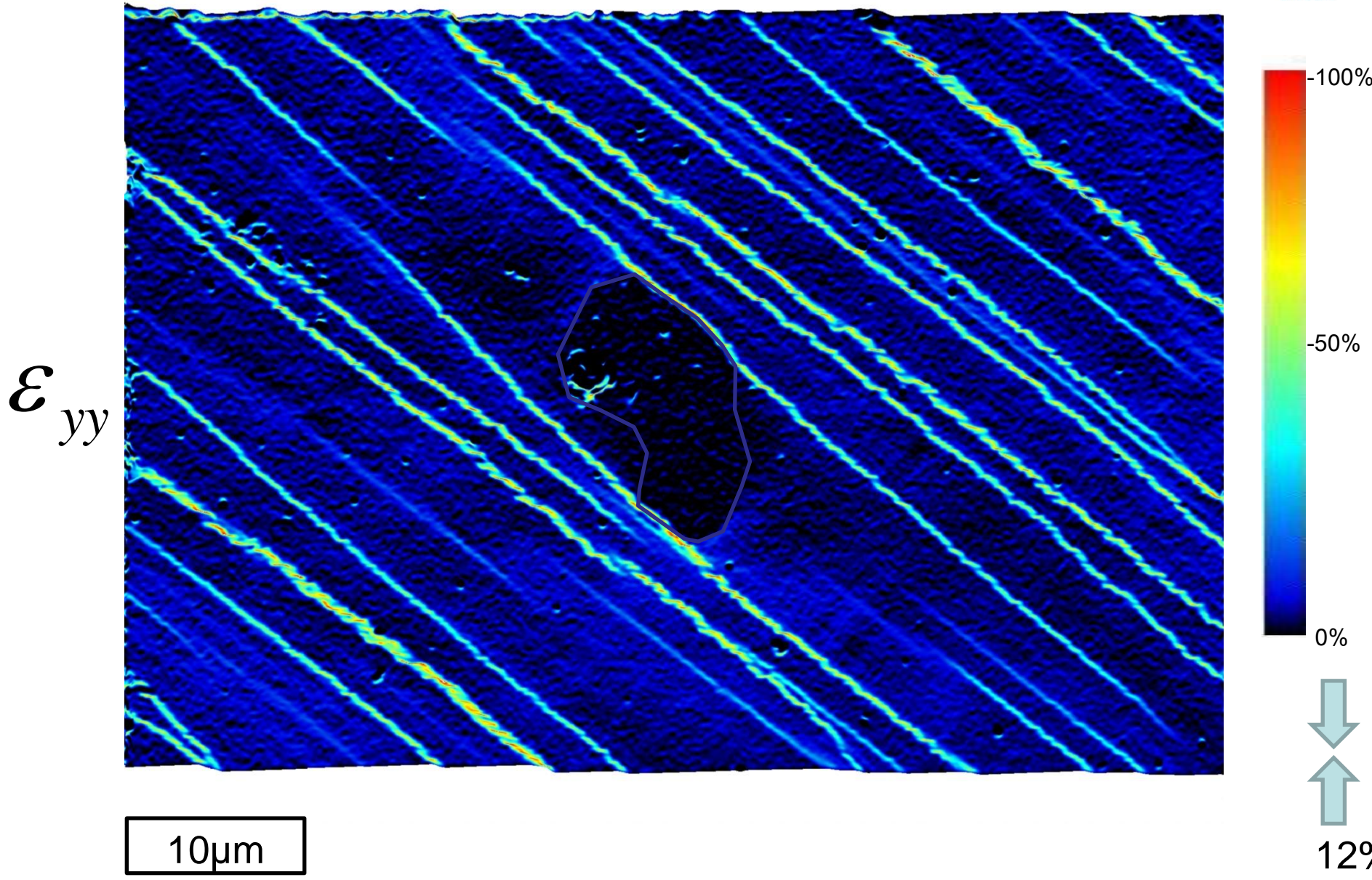
ϵ_{yy}



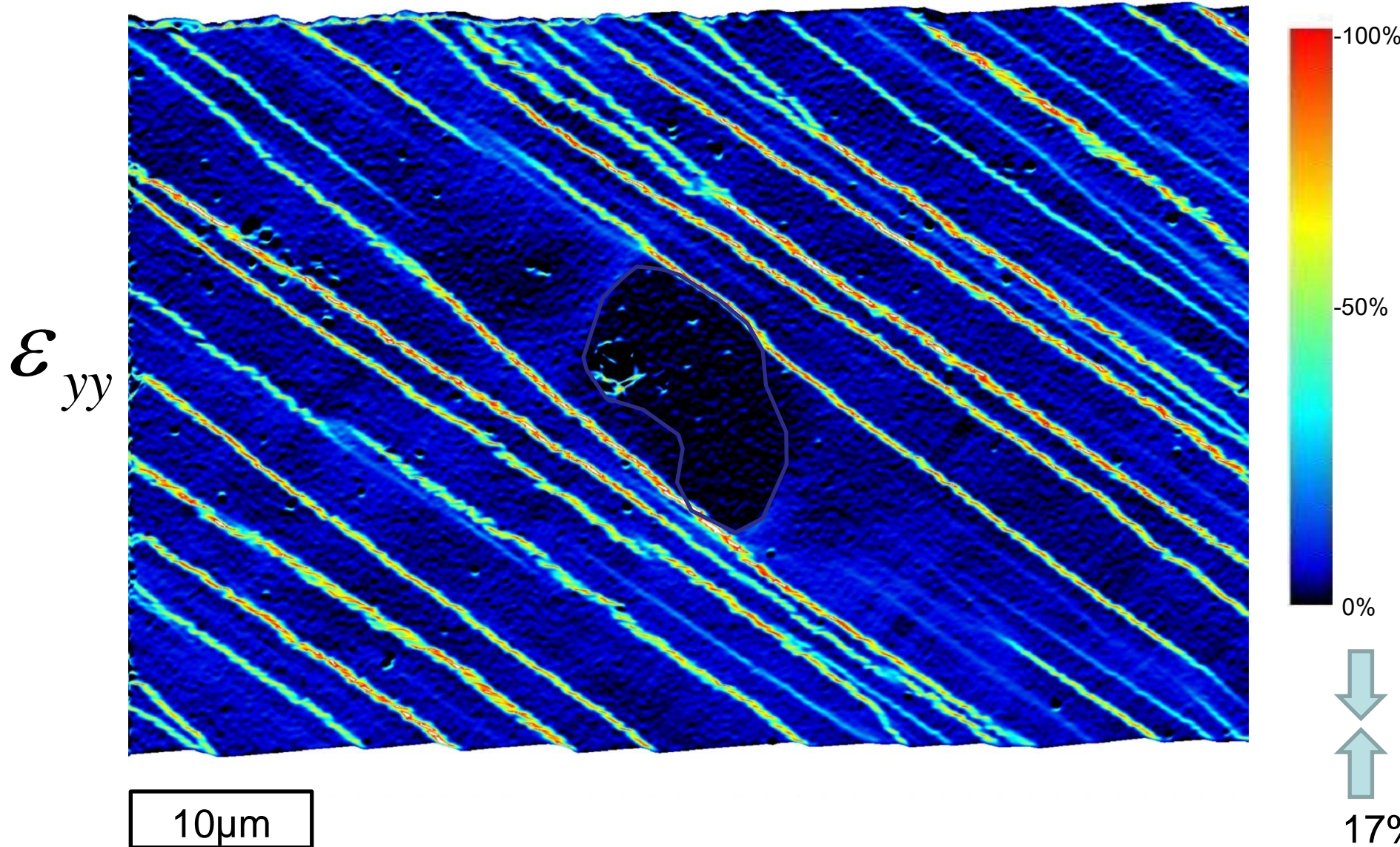
10 μ m

5%

Al-Si Local strain evolution

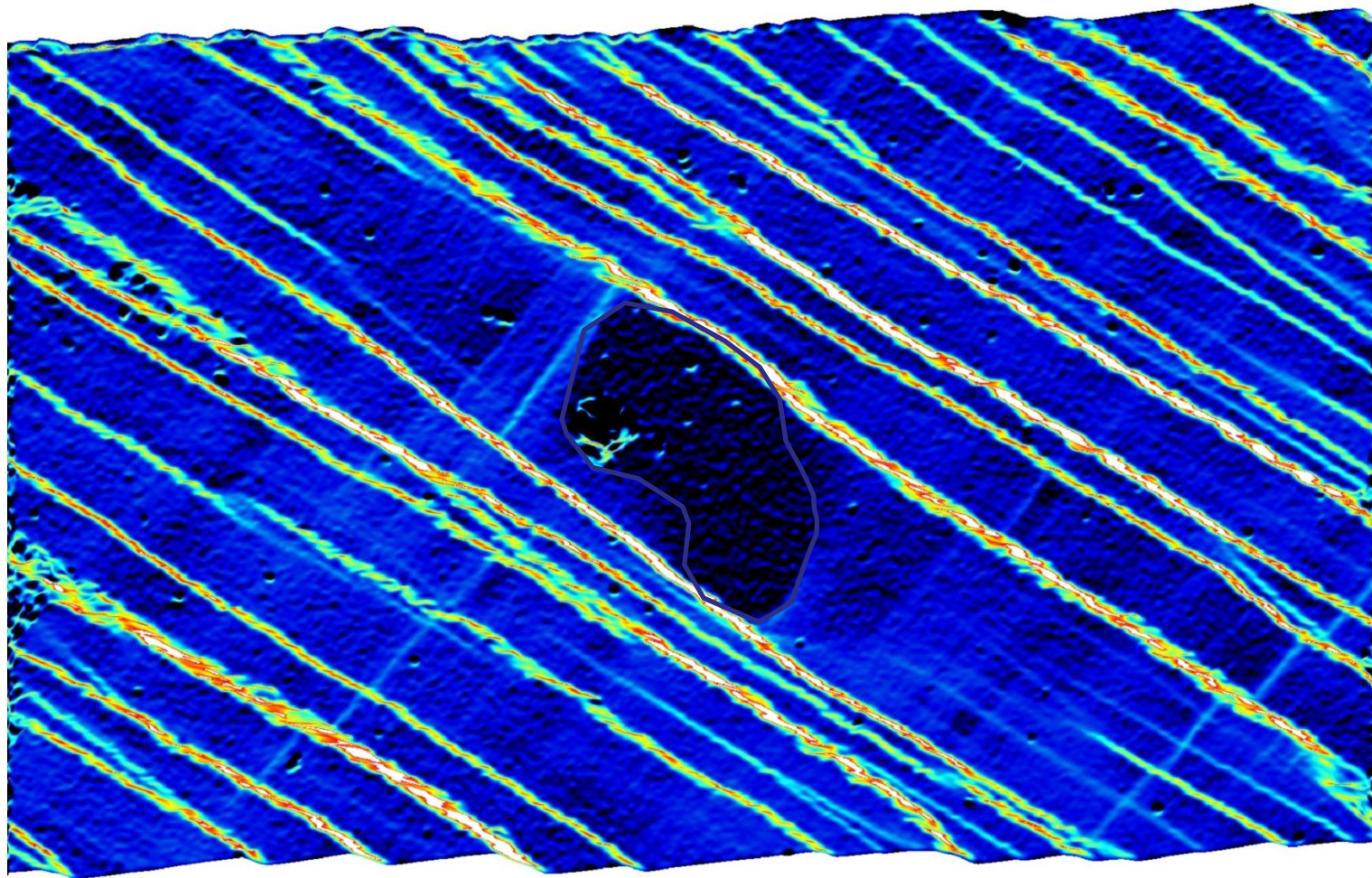


Al-Si Local strain evolution

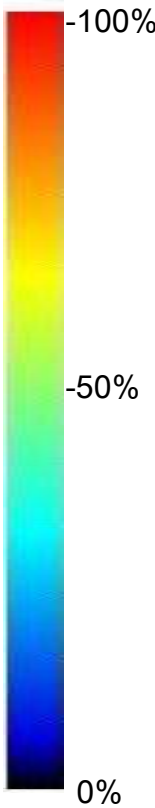


Al-Si Local strain evolution

ϵ_{yy}

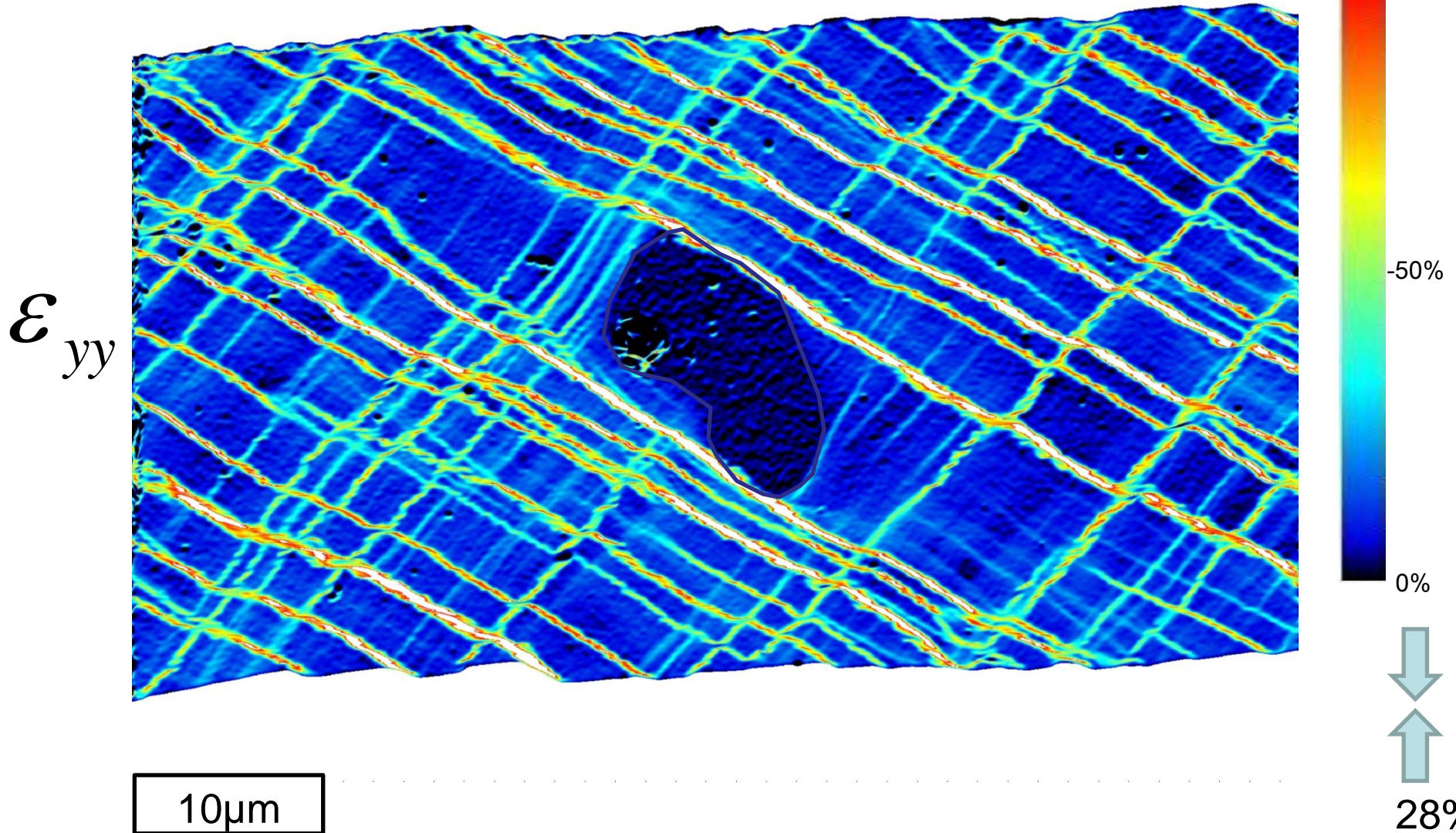


10 μ m



22%

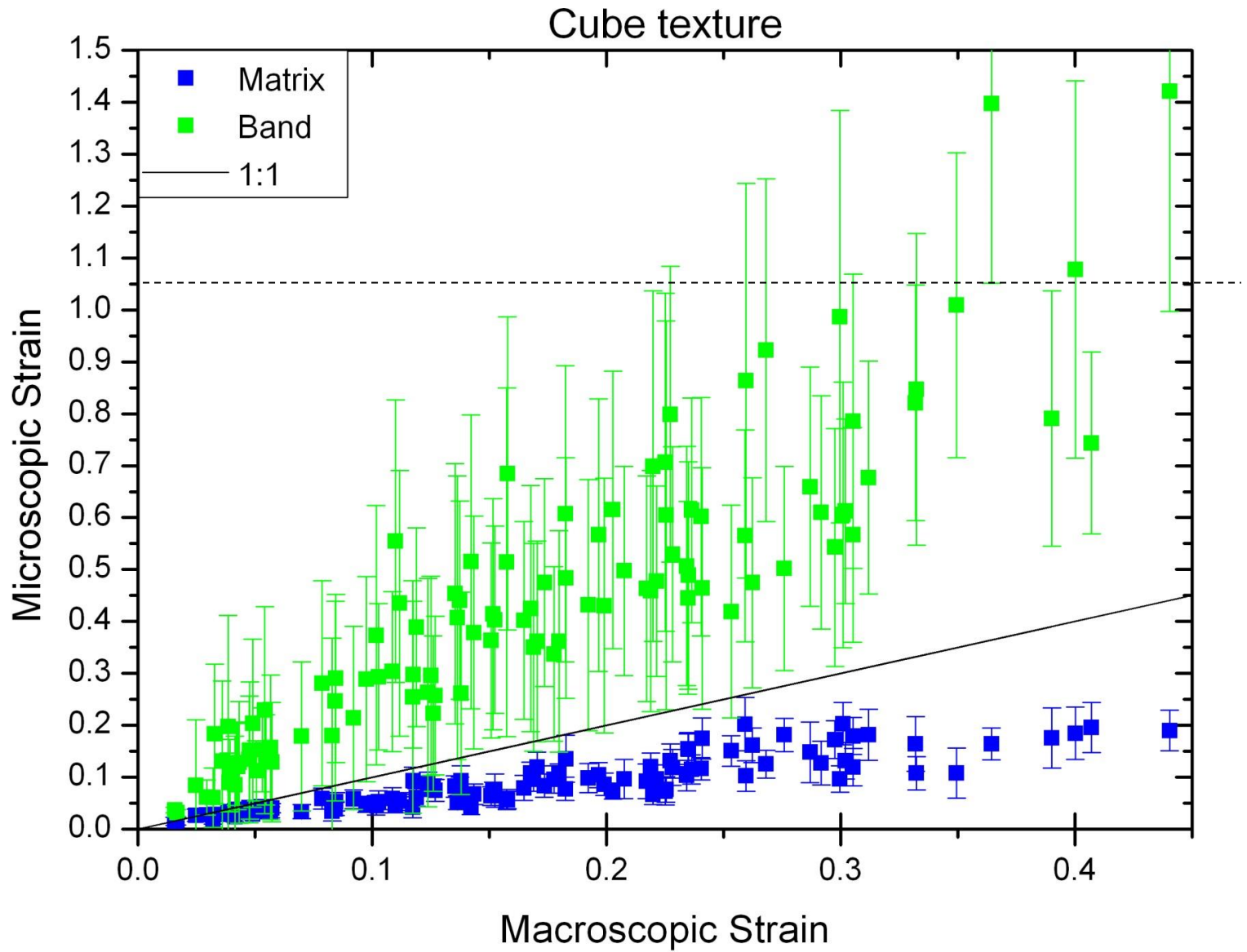
Al-Si Local strain evolution



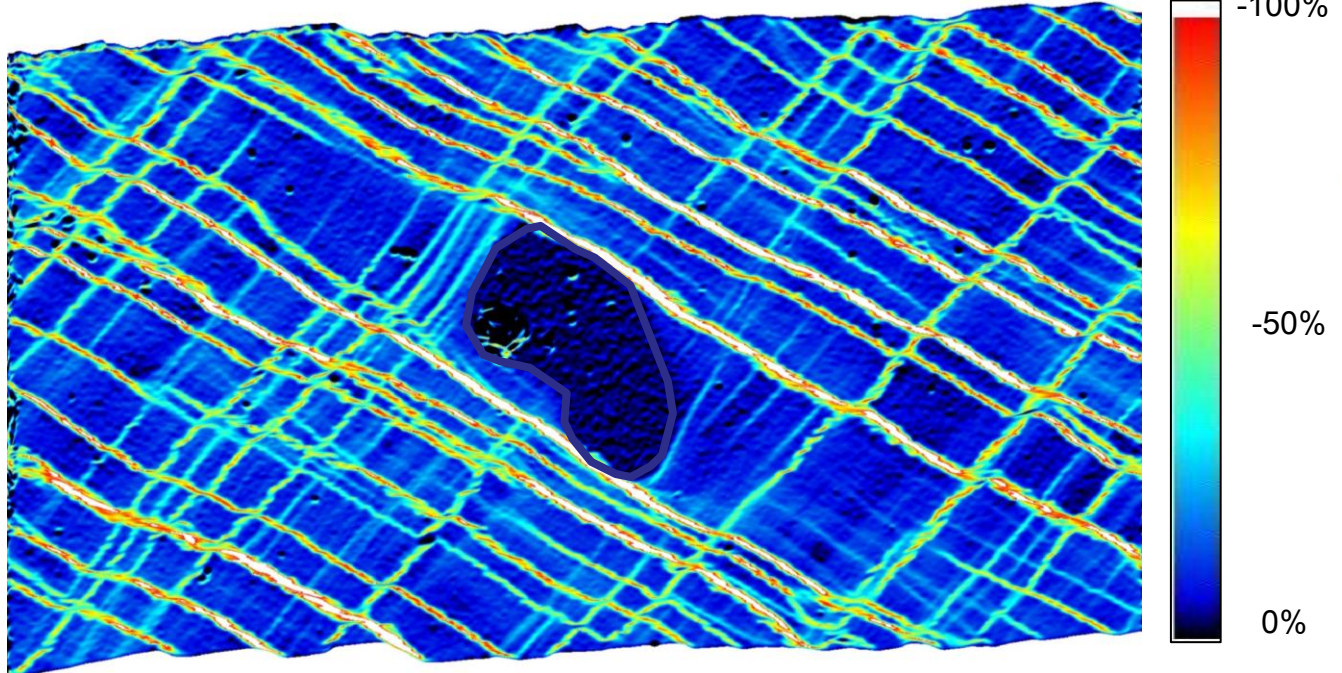
Al-Si strain heterogeneity – Bands vs Matrix

MANCHESTER
1824

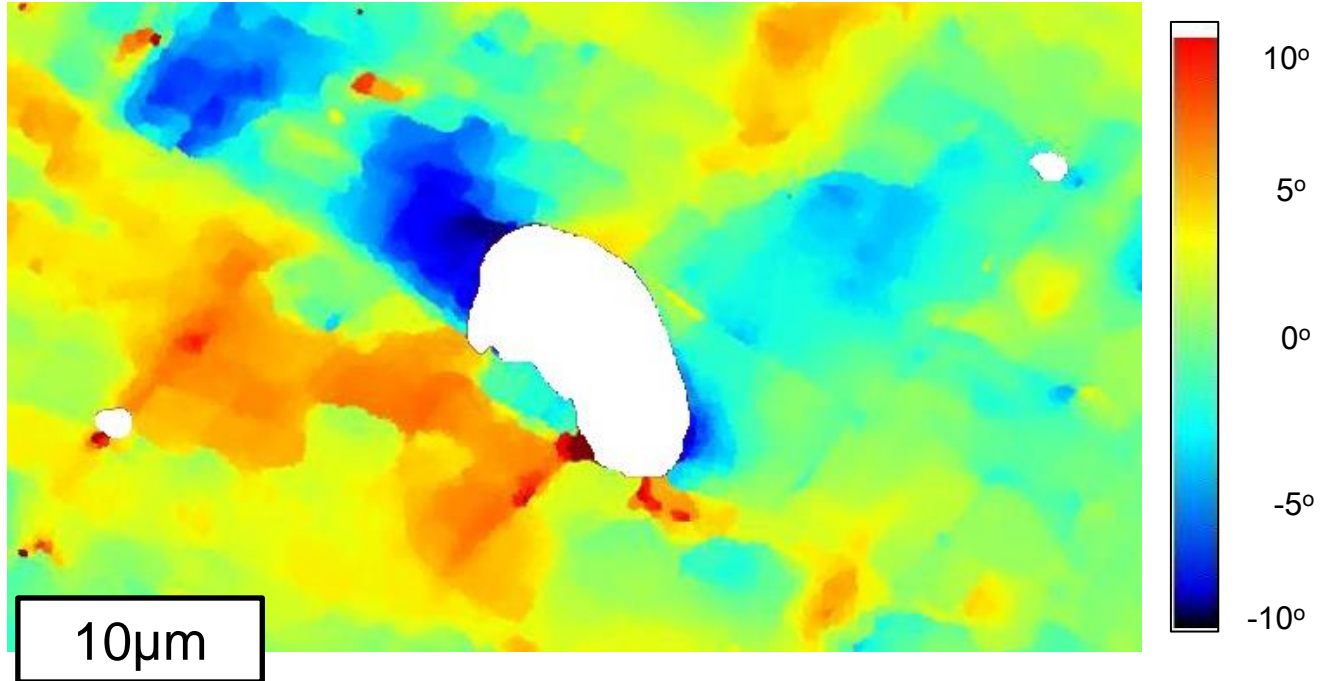
The University of Manchester



DIC strain

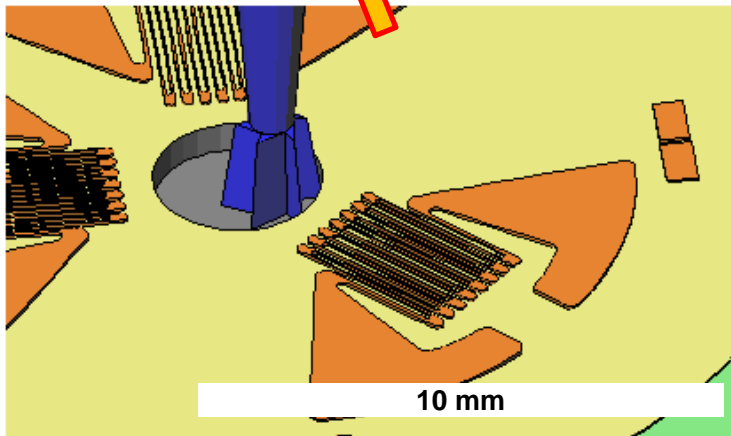


EBSD
rotation



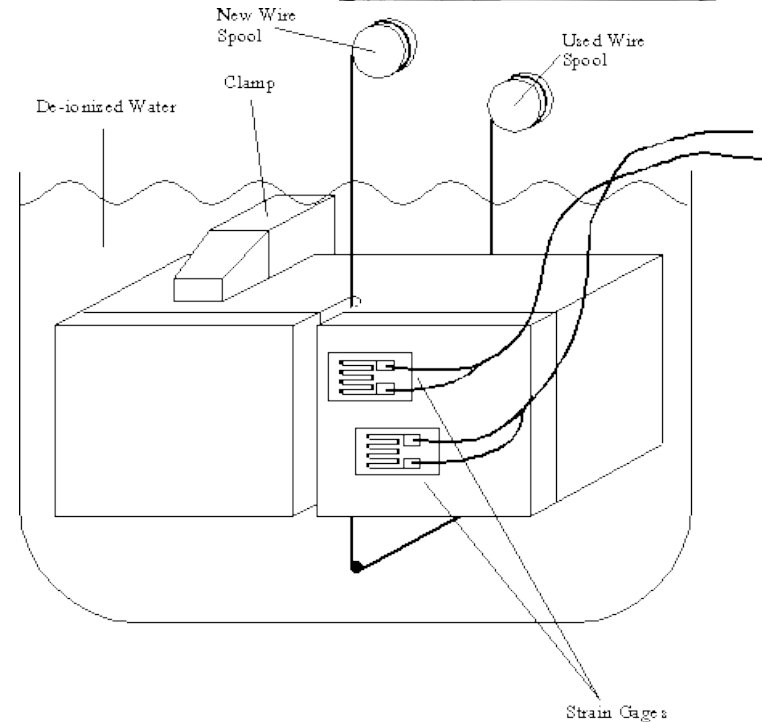
Stress can be measured at the mm scale...

IHD (incremental hole drilling)

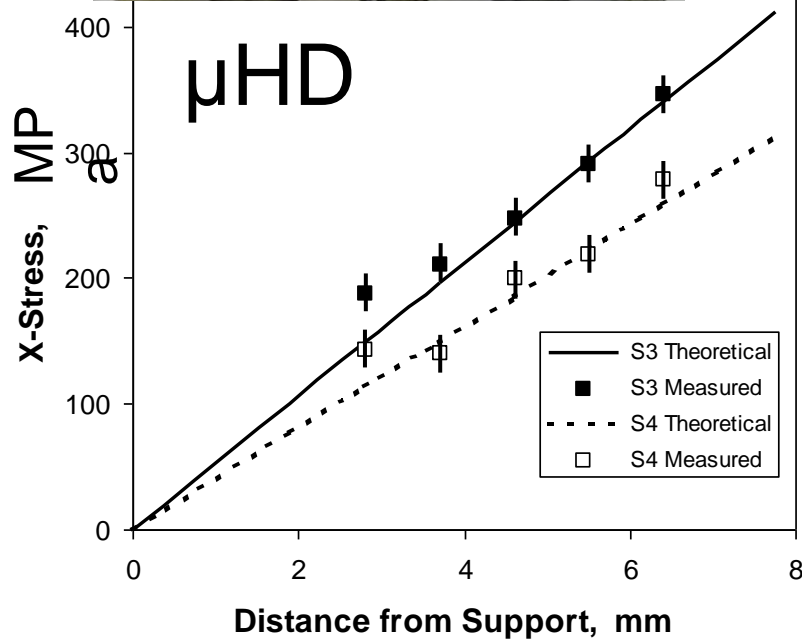
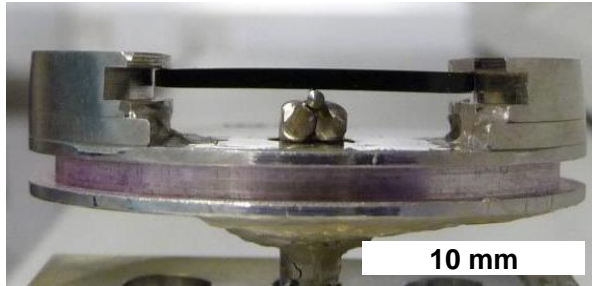


Gary S. Schajer (Uni. British Columbia, Canada)

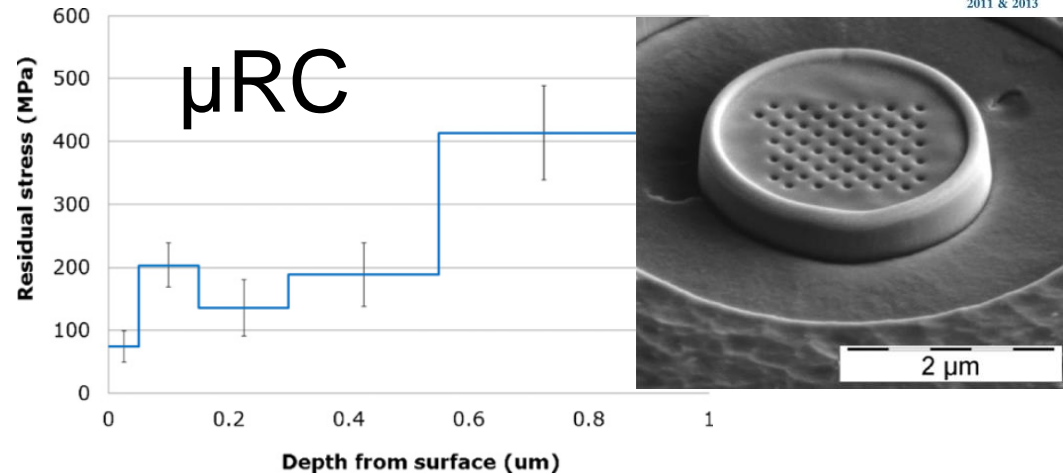
Slotting (Crack Compliance)



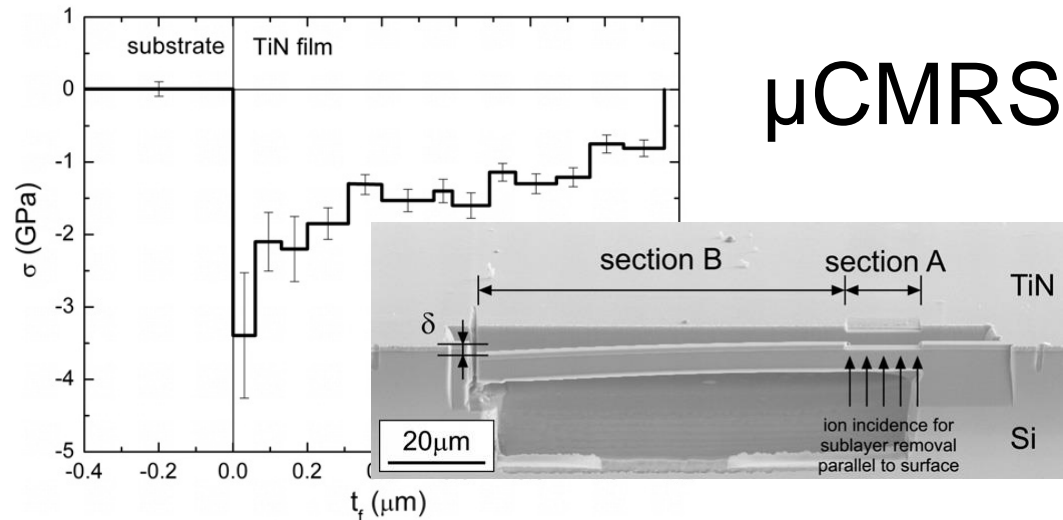
Michael B. Prime (Los Alamos National Lab. USA)



Schajer GS, Winiarski B, Withers PJ. *Exp. Mech.* 2012



Sebastiani M et al. *Mat. Sci. Eng. A* 528 (2011) 7901–7908



Massl S. et al. *Thin Solid Films* 516 (2008) 8655–8662

Mapping stress at the micron scale...

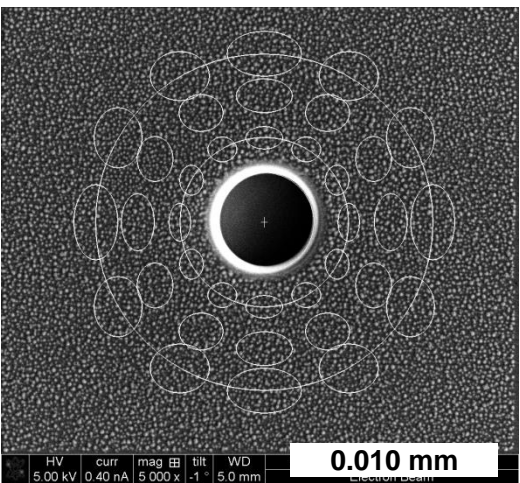
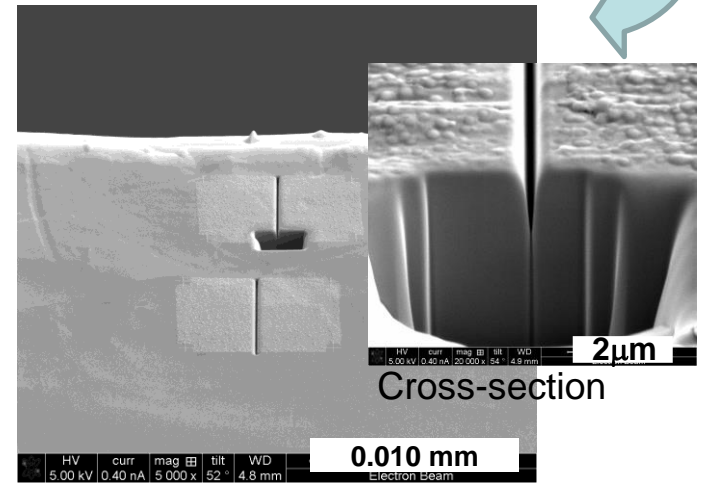
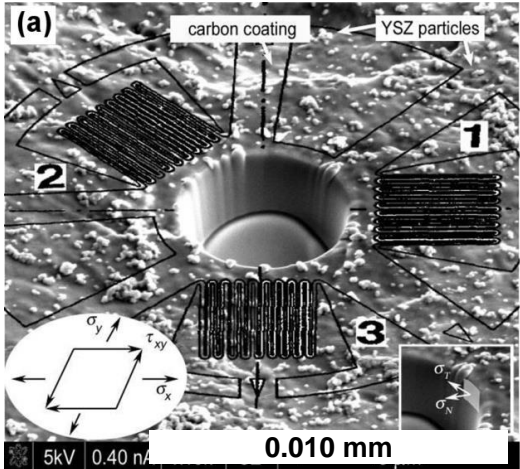


$$\epsilon_x(H) = \int_{h_1}^{h_2} g(H, h) \sigma_x(H) dH$$

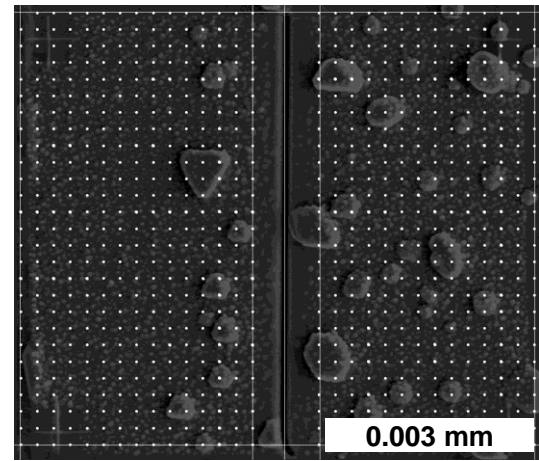


Micro-hole drilling

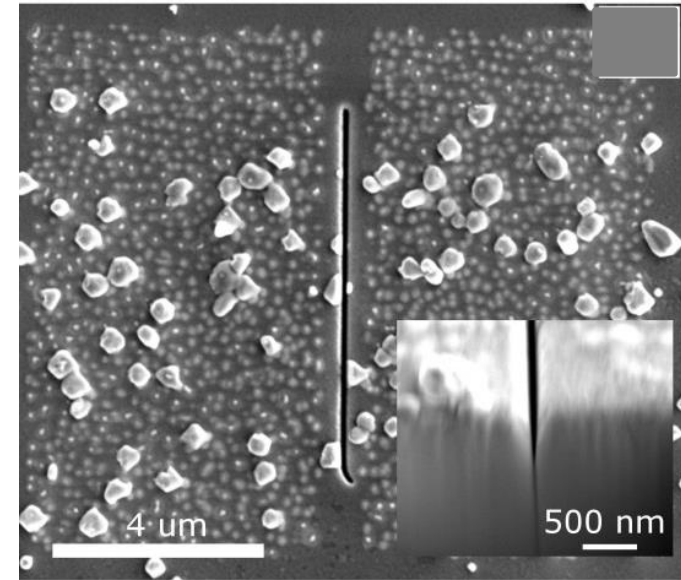
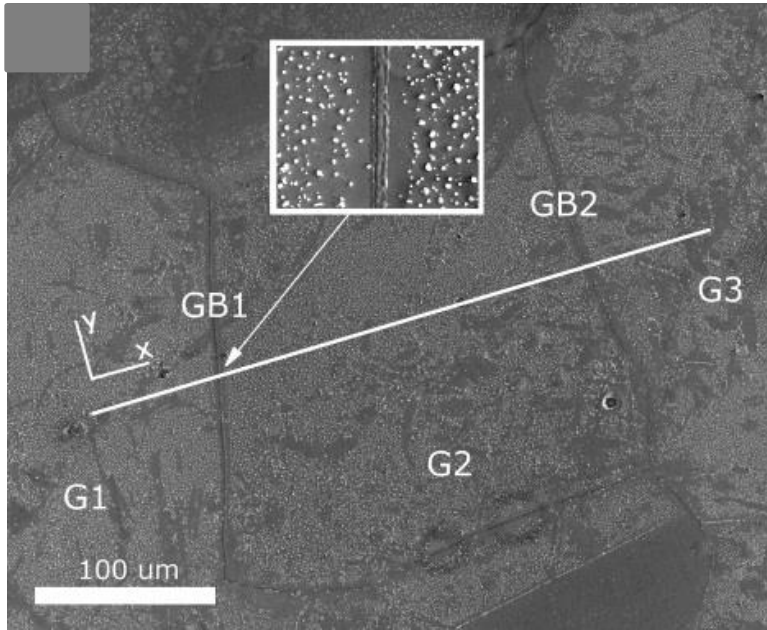
Micro-slotting



$$\epsilon_x(H) = \int_{h_1}^{h_2} g(H, h) \sigma_x(H) dH$$

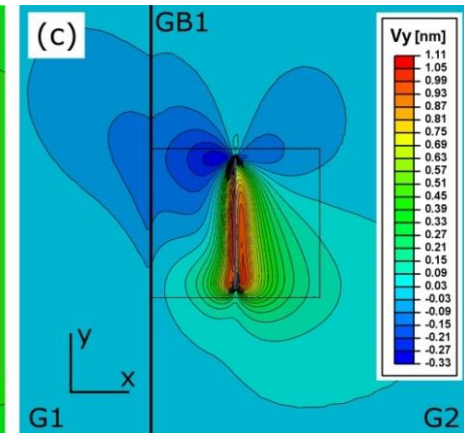
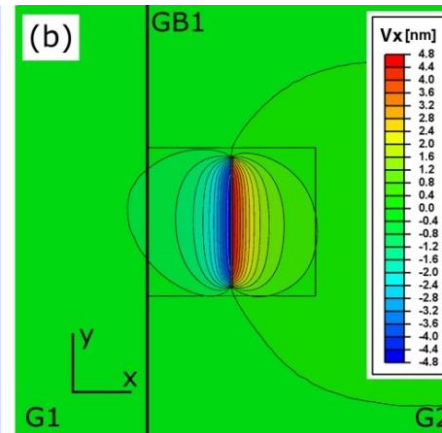
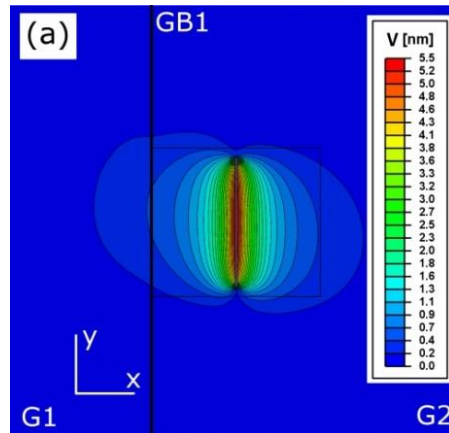
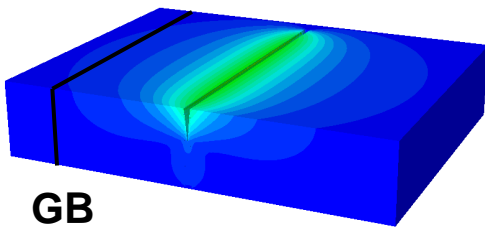


Mapping stresses within Alloy 600 grains



Alloy 600 subjected to low pressure hydrogenated steam

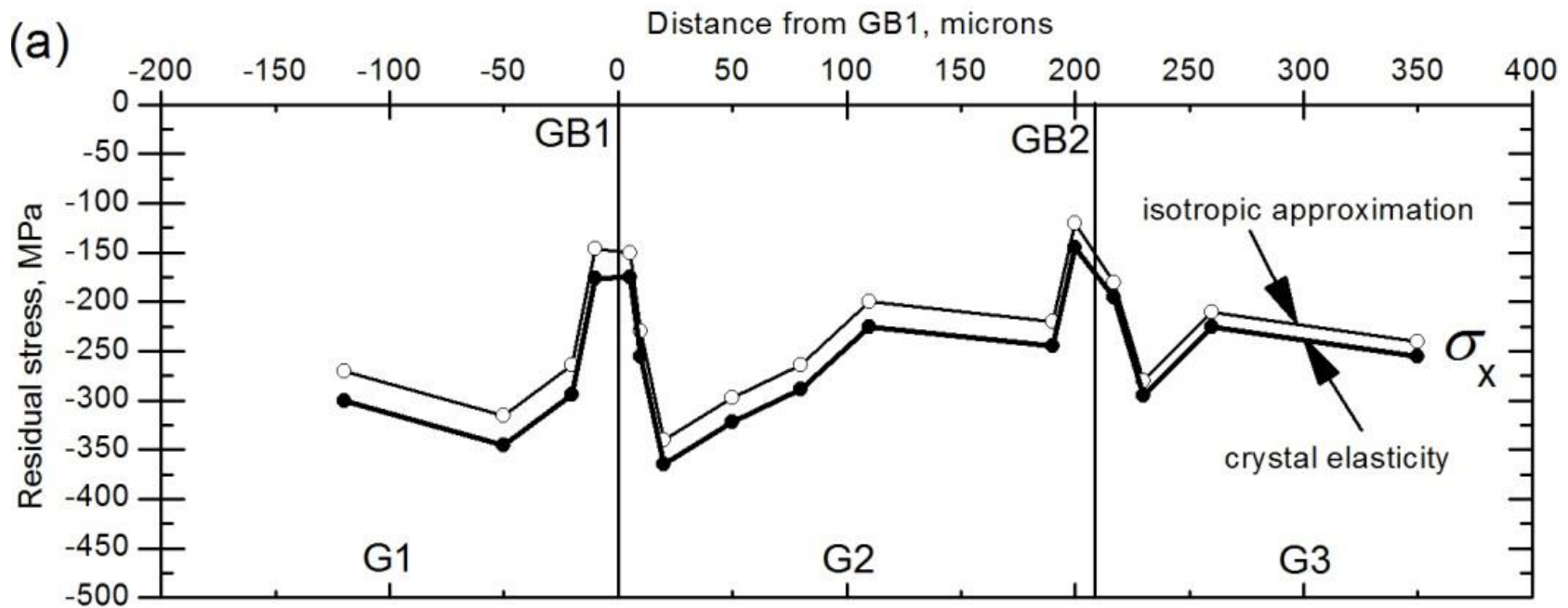
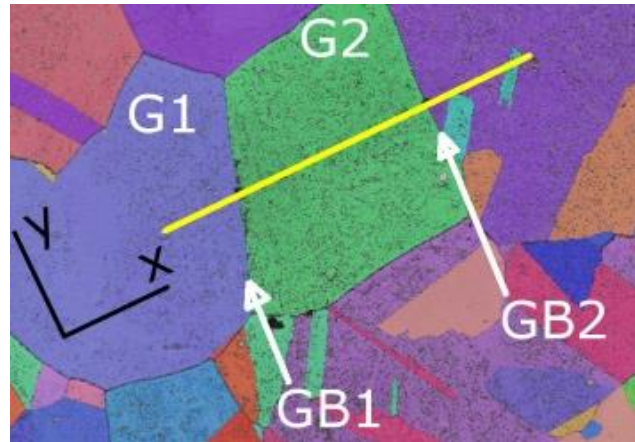
3-D FEA model



Intragranular RS in Alloy 600

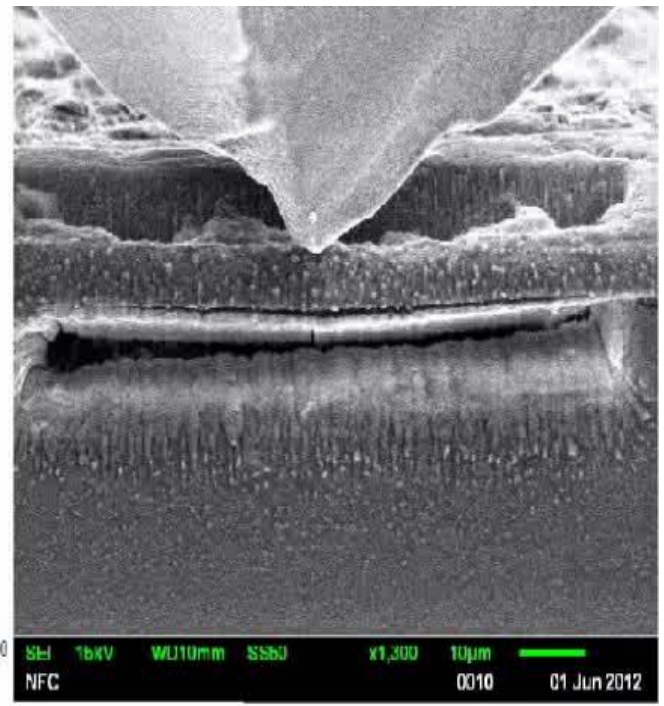
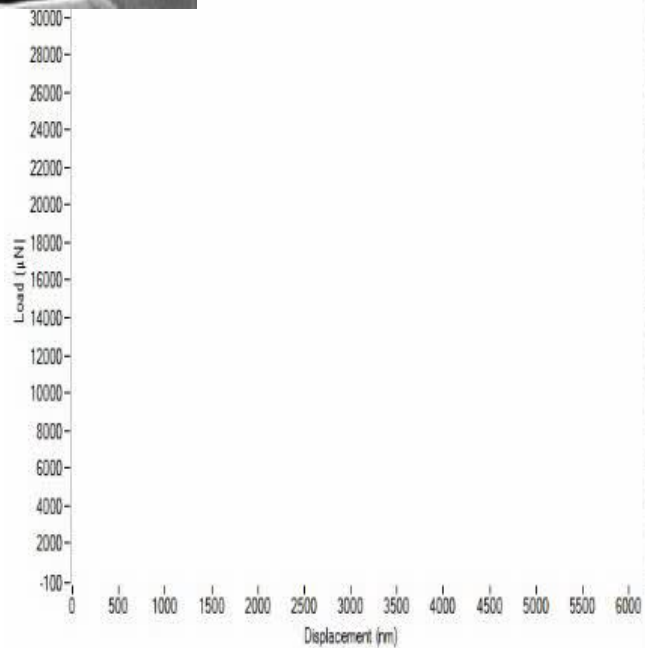
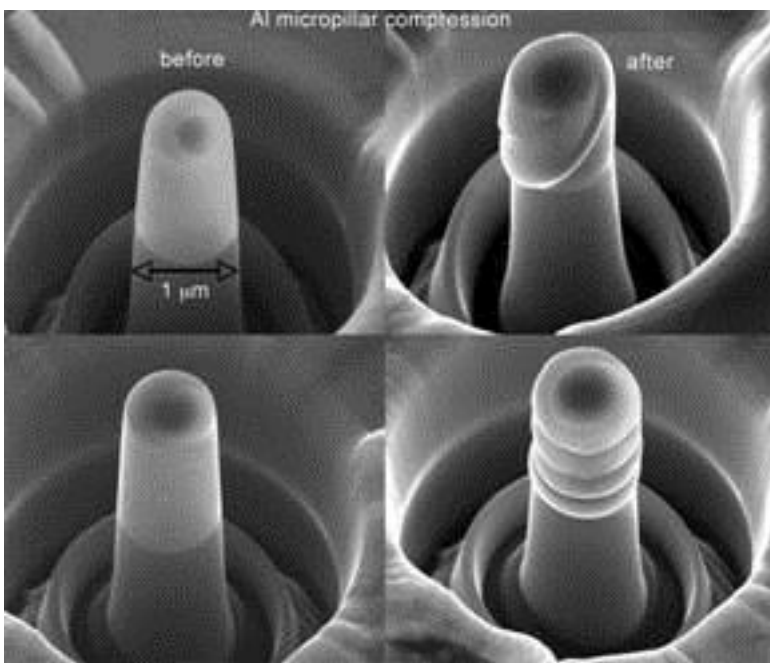


(micro-
slotting)



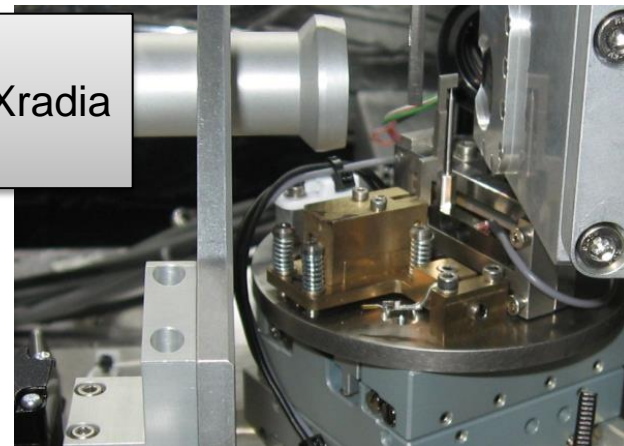
Mechanical characterisation at the hundreds of nanometers scale.....

Nanoindentation



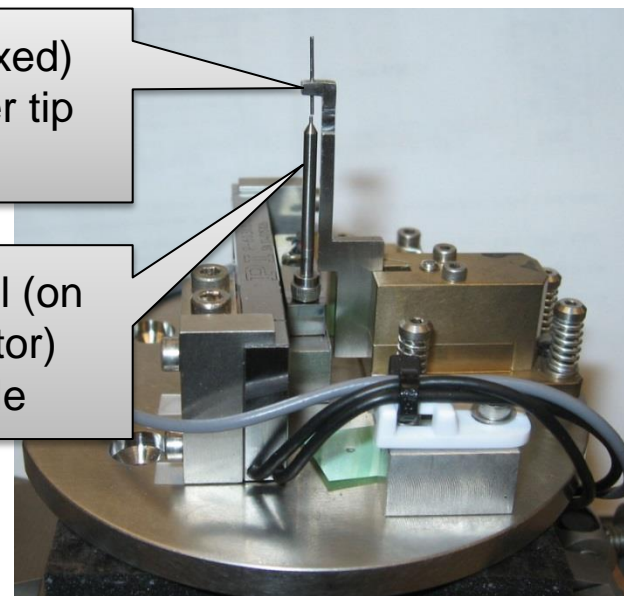
- Mechanical load cell with three operating modes
 - Compression
 - Indentation
 - Tension
- Compatible with Xradia 800/810 Ultra (incl. UltraXRM-L200, nanoXCT-200)
- Preliminary specs:
 - Piezo actuator for closed loop displacement control
 - Strain gauge force sensor, <0.1% sensitivity
 - Option 1: 9 N max force
 - Option 2: 0.8 N max force
 - Allows +/-70° tomography in Xradia Ultra
 - Customizable anvil tips for different operating modes, sample types and experimental designs
- Prototype currently in test phase

Load cell installed in Xradia 810 Ultra



Top anvil (fixed) with indenter tip or flat anvil

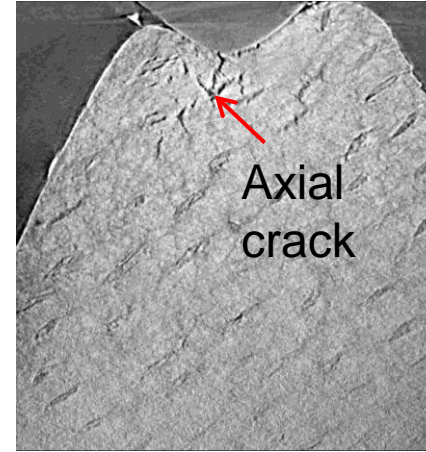
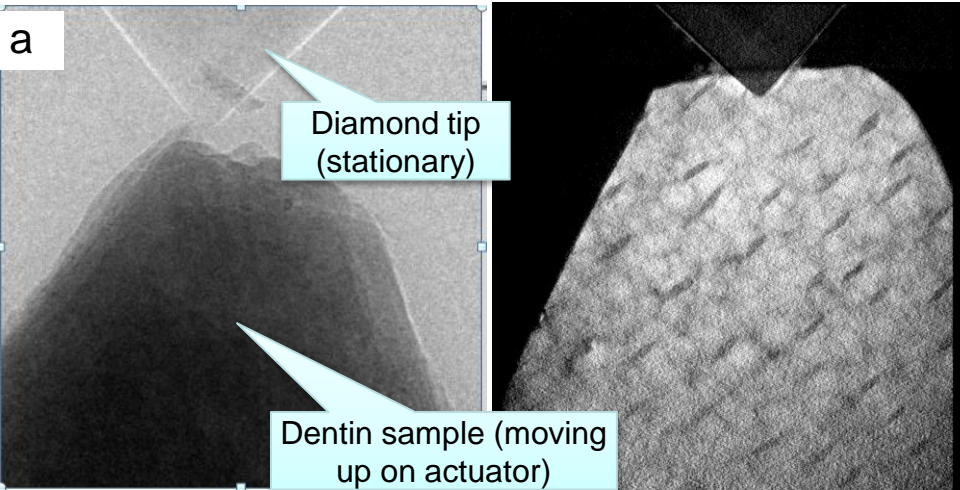
Bottom anvil (on piezo actuator) holds sample



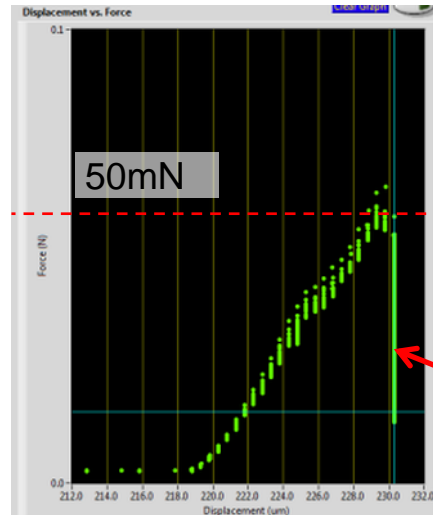
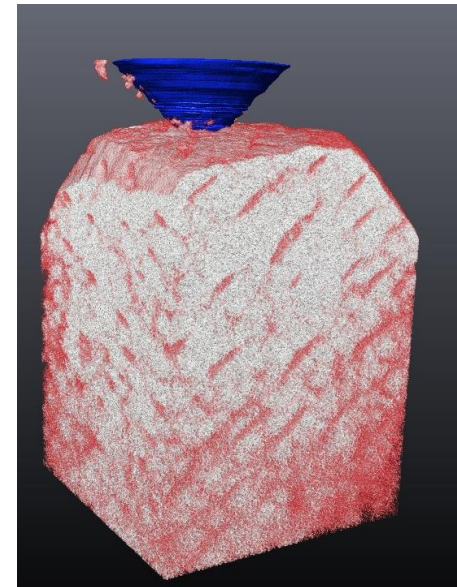
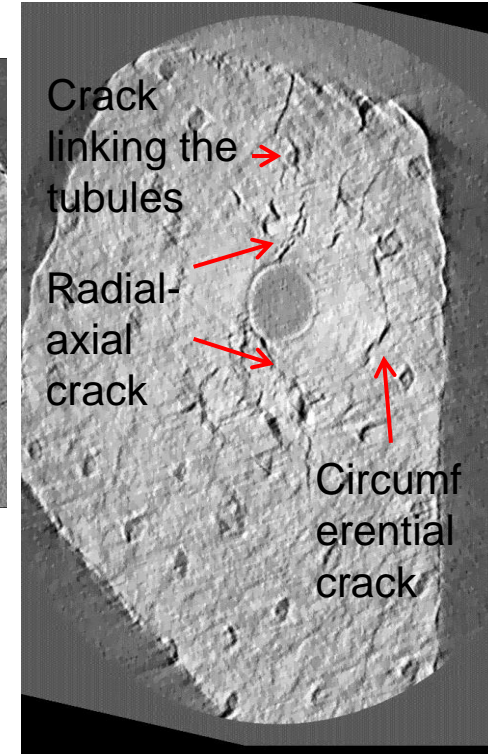
ZEISS

Xradia Ultra load cell – initial results: In situ indentation / cracking of dentin

Diamond tip landing on Dentin (2D series, phase contrast, 65 um FOV)



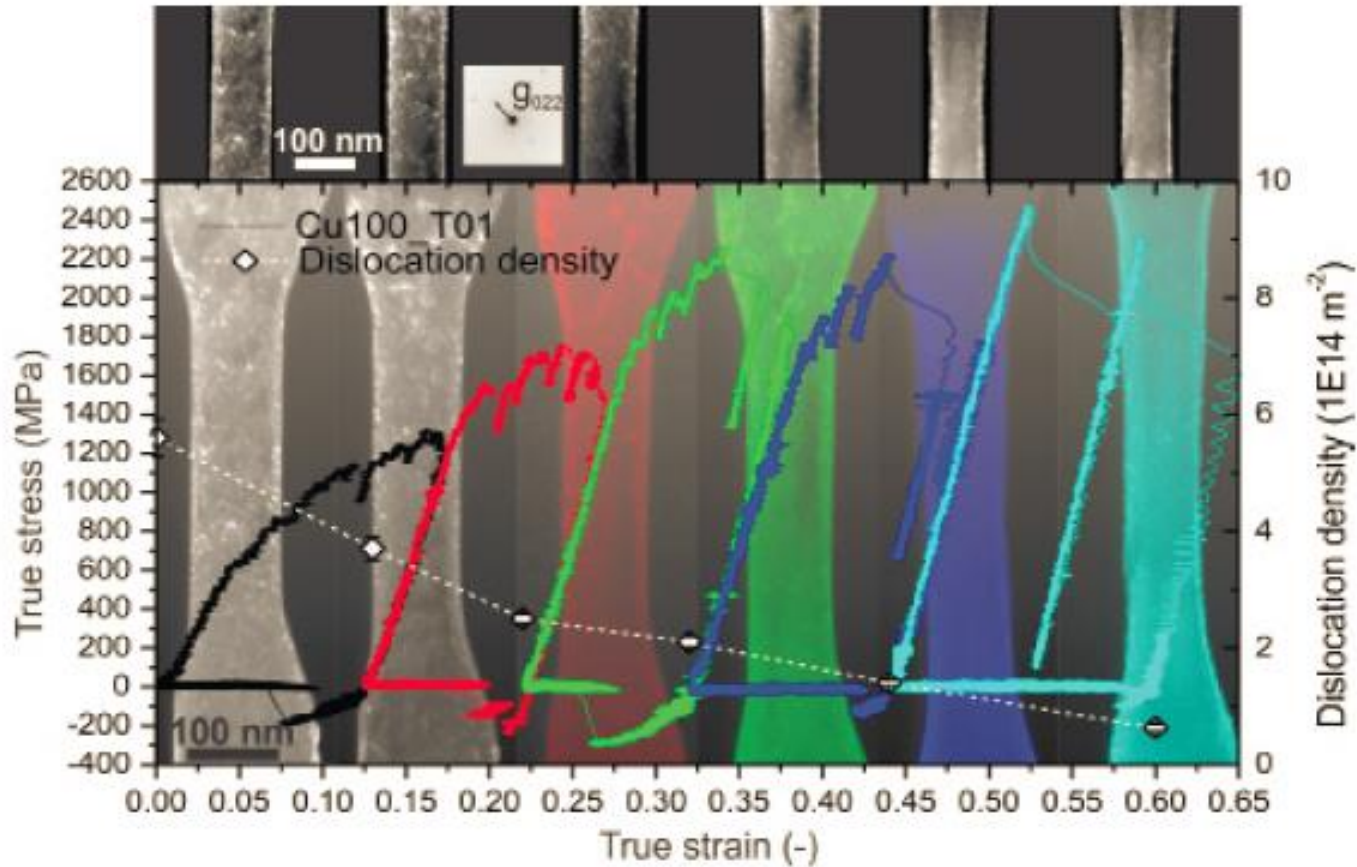
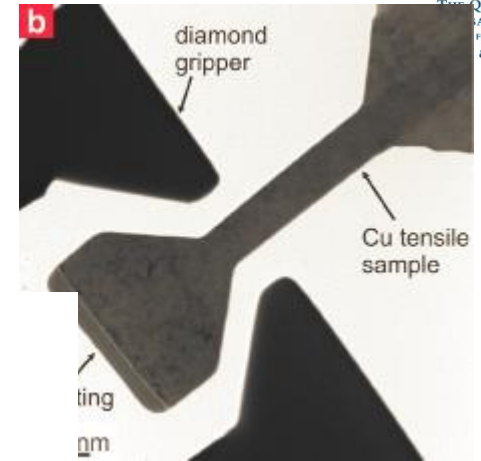
Horizontal section



Force-displacement curve: Abrupt fracture event occurred here (c)



Loading in situ within TEM



Courtesy Hysitron

Concluding remarks

- Now able to track the same region of interest across time and multiple length scales
- Using a correlative multi-scale framework can now determine for the same region of interest the mechanical properties as a function of length scale
 - Better understanding of microstructure property relationships
 - Better understanding of how micro-structuring can be used to control properties
- Inverse/Virtual fields methods may provide rich spatially variant datasets without the need for idealised test geometries

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BP: Ellen Williams

Open University: Hedieh Jazaeri, Shirley Northover, John Bouchard

Luxfer- Henry Holroyd

Innoval- Geoff Scamans

Paper on correlative tomography:

<http://www.nature.com/srep/2014/140416/srep04711/full/srep04711.html>

Video on pitting example: <https://www.youtube.com/watch?v=P5oUpiVvZVY>

More information: www.imaging.manchester.ac.uk